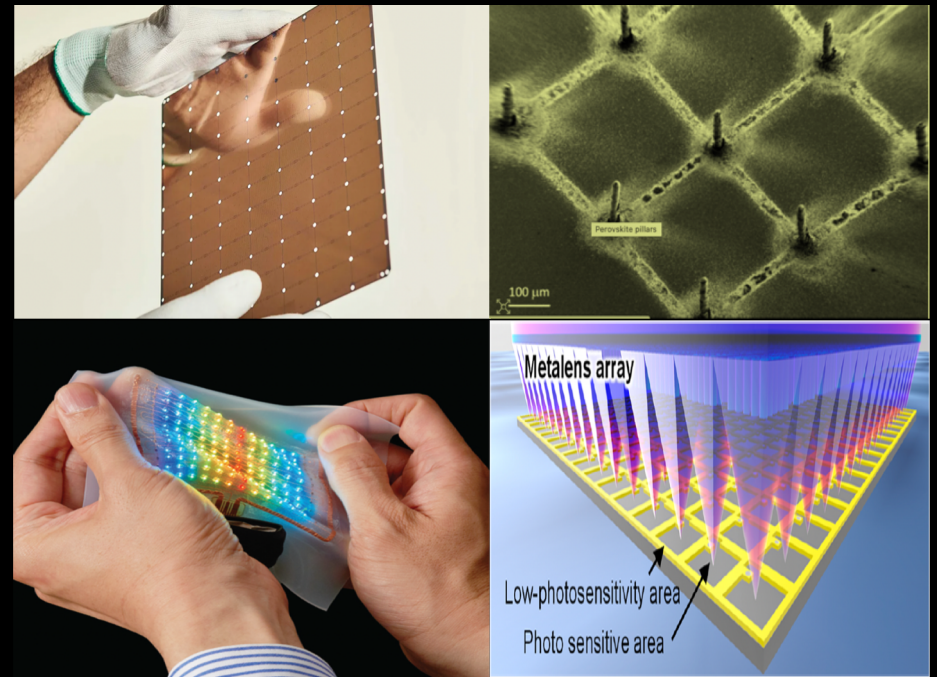


# Radiation Detectors, Imaging What You Cannot See: Silicon and Advanced Techniques



**Cinzia Da Via**

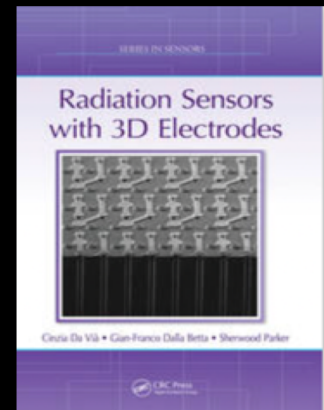
*The University of Manchester, UK & Stony Brook University USA*

# Some Information about myself

- Professor at The University of Manchester (UK)
- Visiting Professor at the University of Stony Brook, New York, USA
- Member of the ATLAS Collaboration at CERN – LHC
- Chief editor Frontiers in Physics, Radiation Detectors and Imaging
- Co-Chair of the EU-ATTRACT Independent Committee
- IEEE WIE International Committee Member 2017-2022
- Member of the IEEE TAB Program on Climate Change
- Distinguished Lecturer and Organizer of the IEEE NPSS Instrumentation School

## Scientific Interests:

- Radiation Detector development : silicon pixels, 3D silicon detectors, fast timing
- Radiation effects in silicon, “Lazarus effect”
- 3D printed detectors, Vertical integrated microsystems
- Quantum Imaging at X-Ray energies



# This lecture

- Brief reminder: Radiation, Radiation interaction with Matter and Radiation Detectors
- **Imaging Radiation with Silicon Detectors:**

Pixel sensors  $\leftrightarrow$  Monolithic and Hybrid

- Basics of Signal formation in silicon sensors
- ~~Basics of radiation effects in silicon sensors~~
- **Examples of applications in High Energy Physics, medicine, Environmental Monitoring and Energy Harvesting**
- A brief look at the future

# Imaging radiation



Web cams  
machine vision,



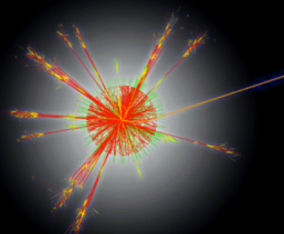
Smart phones  
automotive, security etc..



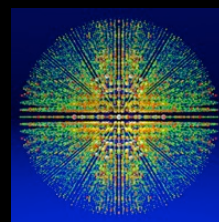
photo cameras



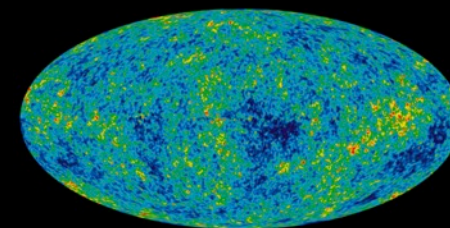
Medical imaging  
Quantum Imaging.....



HEP



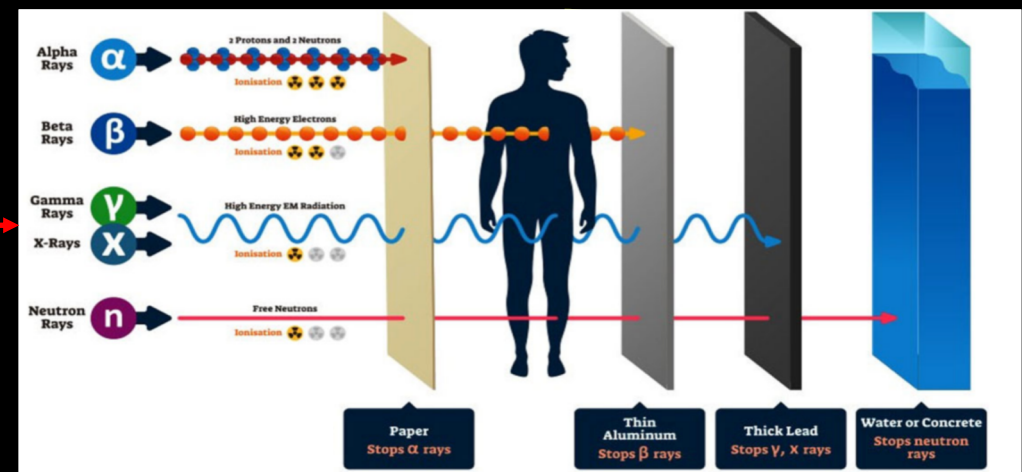
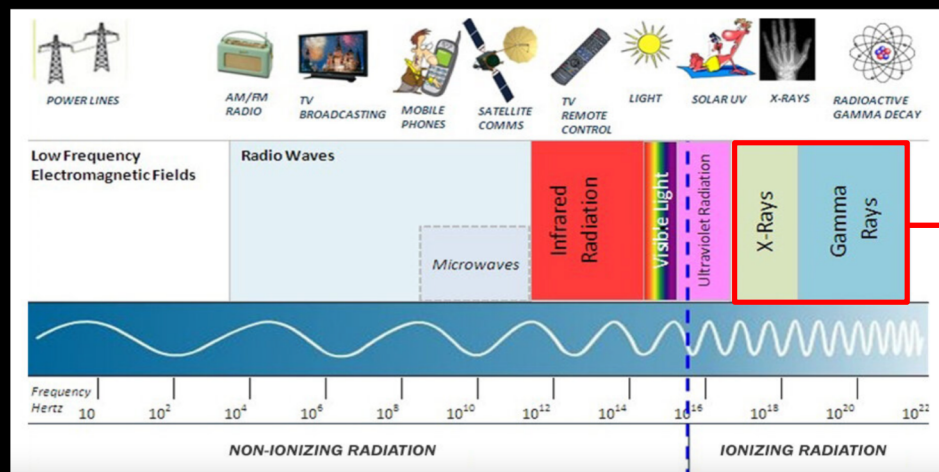
x-ray crystallography



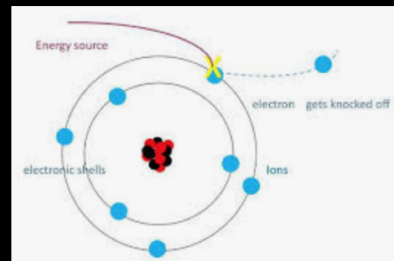
cosmology

# What is Radiation and its interaction with matter - recap

Radiation can be defined as the propagation of energy through space or matter in the form of electromagnetic waves or energetic particles.



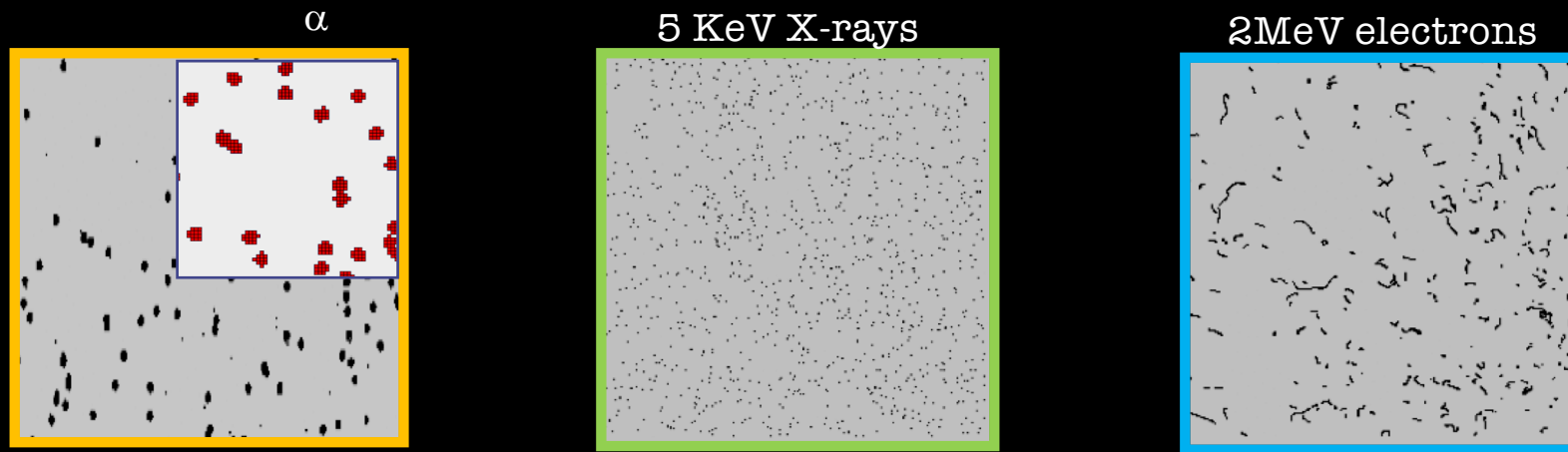
**Ionizing** has enough energy to knock an electron from an atom



**Non-ionizing** does not have enough energy to ionize atoms but generate heat in the material it interacts with.

# Particle “signatures” with the Timepix readout electronics

→ See presentation from S. Pospisil



- ◆  $^{241}\text{Am}$  alpha source gives clusters of  $\sim 5 \times 5$  pixels measured with the MEDIPIX-USB device and a  $300 \mu\text{m}$  thick silicon sensor. The clusters are shown in detail in the inset. The cluster sizes depend on particle energy and threshold setting.
- ◆ Signature of X-rays from a  $^{55}\text{Fe}$  X-ray source. Photons yield single pixel hits or hits on 2 adjacent pixels due to charge sharing.
- ◆ A  $^{90}\text{Sr}$  beta source produces “tracks” in the silicon detector.
- ◆ A pixel counter is used just to say “YES” if individual quantum of radiation generates in the pixel a charge above the pre-selected threshold

# The semiconductor revolution 1947

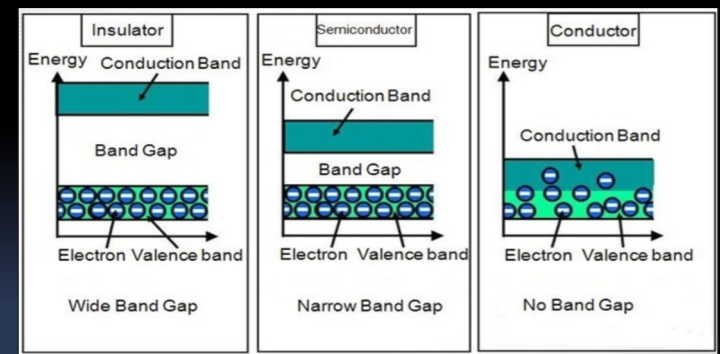
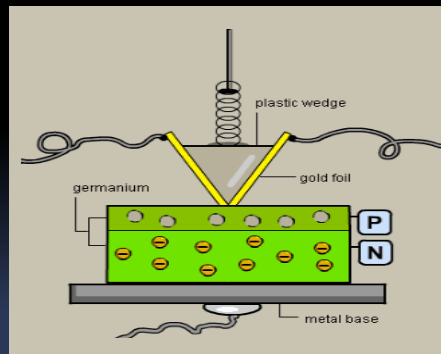
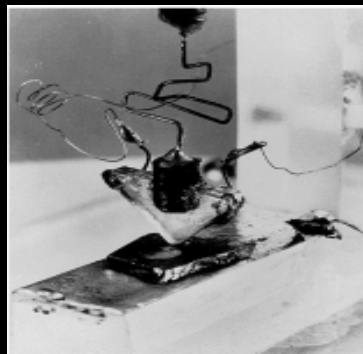


First transistor invented 1947 by William B. Shockley, John Bardeen and Walter Brattain (Nobel Prize 1956)

First semiconductor particle sensor: Pieter Jacobus Van Heerden, *The Crystalcounter: A New Instrument in Nuclear Physics*. University Math Naturwiss, Fak (1945).

*CCD Nobel prize Boyle Smith 2009*

Semiconductor a material that has a conductivity between a conductor and an insulator; electricity can pass through it, but not very easily



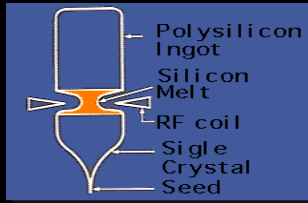
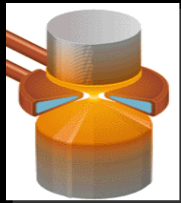
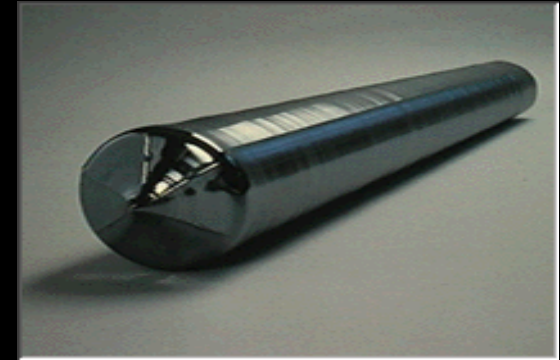
The point contact germanium transistor

# SILICON: from sand to wafer

Silicon (silicates) makes up 27.7% of the Earth's crust by mass and is the second most abundant element (oxygen is the first)



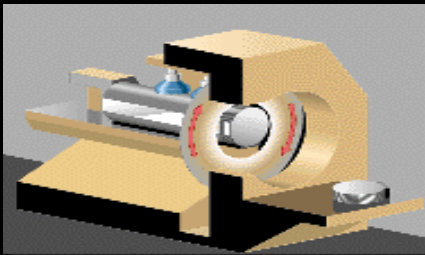
a) The sand is cleaned and further purified by chemical processes. It is then melted. Then a tiny concentration of phosphorus (boron) dopant is added to make n (p) type poly-crystalline ingots



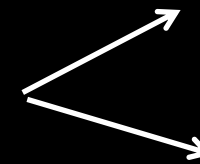
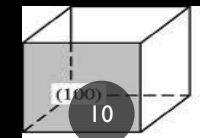
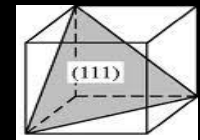
b) Single-crystal silicon is obtained by melting the vertically oriented poly-silicon cylinder onto a single crystal "seed" --- called "Float Zone- $\rightarrow$  FZ"



c) Wafers of thickness 200- 500 $\mu$ m are cut with diamond encrusted wire or disc saws.



Note: the crystal orientation matters!  
<111> and <100> crystals can influence the detector properties eg. capacitance

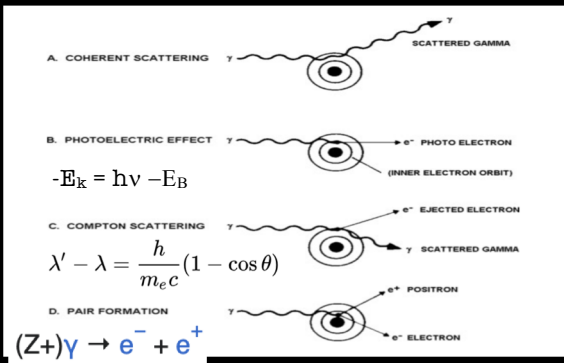
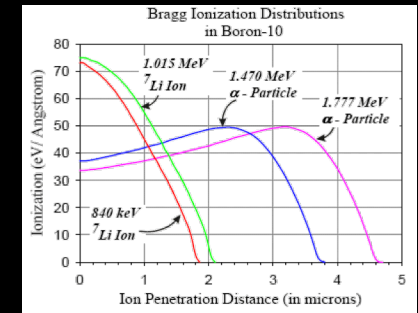
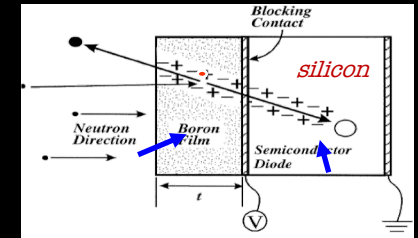
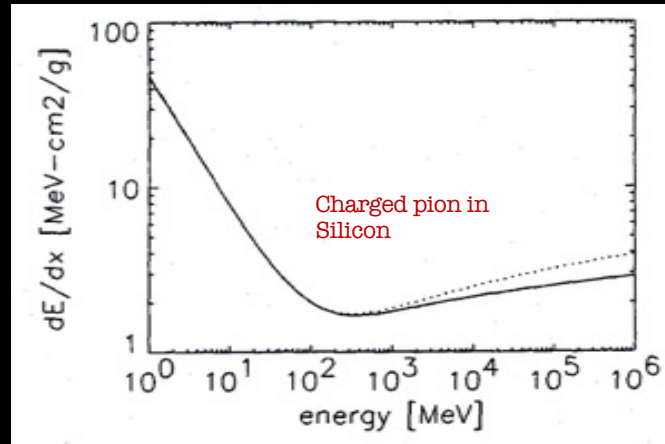
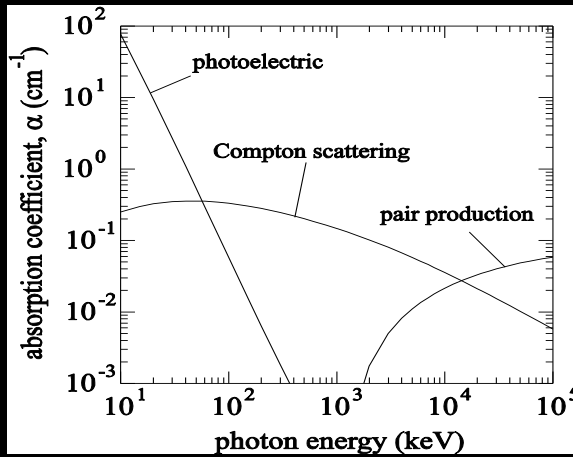




# Interaction of radiation with silicon-

Quantum mechanics in action!!!!

See presentation from A. Lyoussi



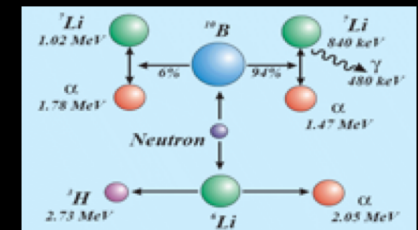
**Ionizing particles:**

**Bethe-Bloch equation:**  
average/mean amount of energy lost due to ionization per unit of distance in the media)

$$-\frac{dE}{dx} = \frac{4\pi}{m_e c^2} \cdot \frac{n z^2}{\beta^2} \cdot \left(\frac{e^2}{4\pi\epsilon_0}\right)^2 \cdot \left[ \ln\left(\frac{2m_e c^2 \beta^2}{I \cdot (1 - \beta^2)}\right) - \beta^2 \right]$$

$$n = \frac{N_A \cdot Z \cdot \rho}{A \cdot M_u}$$

Si bandgap = 1.12 eV



**Photons:**

-Photoelectric, Compton, pair production

**Neutrons:** Alpha Bragg peak

# Photons

- Photons are the quantum particles carrying “electromagnetic energy”
- They have zero mass energy
- They travel at the speed of light

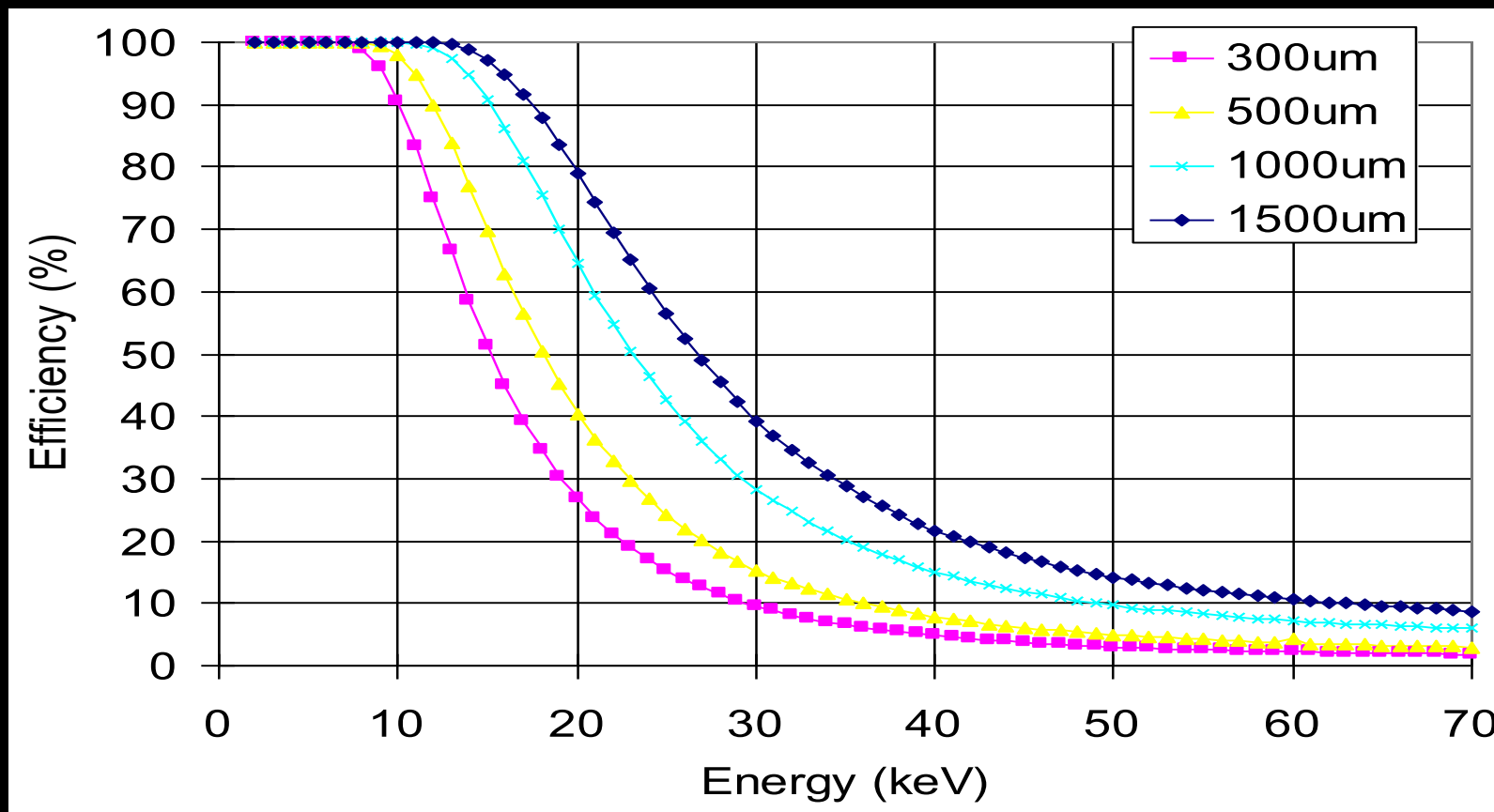
- Their energy is:

$$E_{ph} = h\nu = hc / \lambda$$

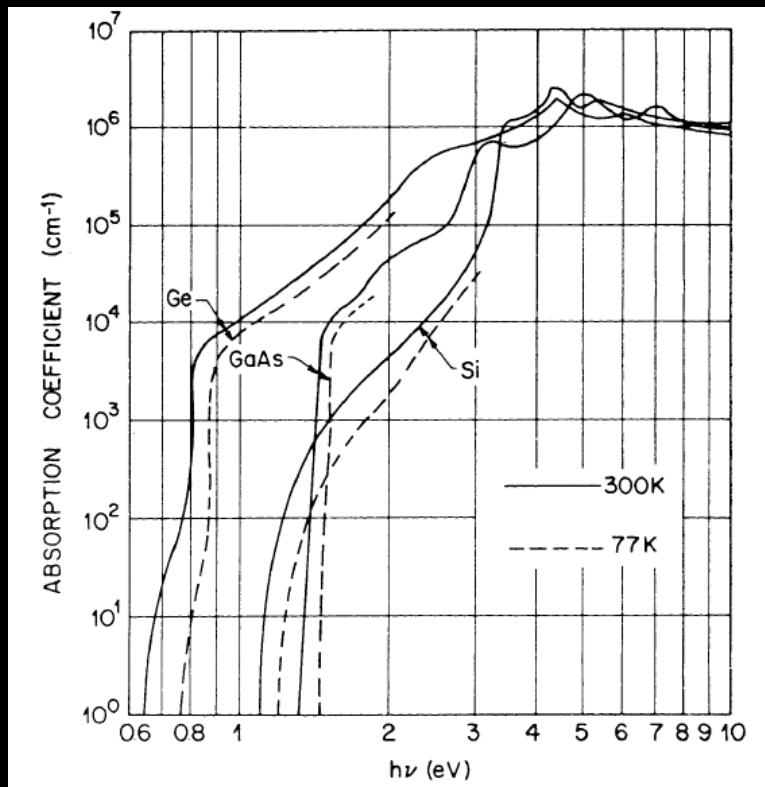
(where  $h$  is the Planck's constant,  $6.62 \times 10^{-34}$  J·s)

- The most important forms of interaction with matter include:
  - Absorption
  - Refraction
  - Transmission/Reflection
  - Diffraction

# X-ray absorption efficiency in Si



# Absorption coefficient



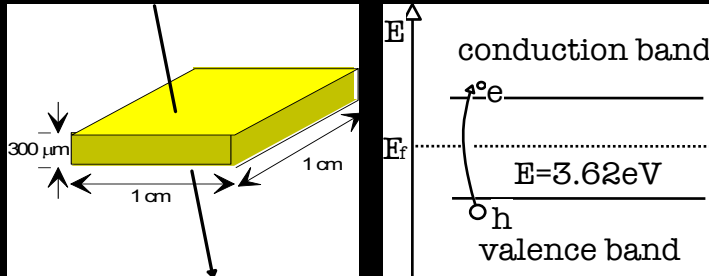
- At low energy the most important parameter is the absorption coefficient  $\alpha$ , that determines the probability of the photon to be absorbed
- $\alpha$  is strongly dependent on  $\lambda$
- The attenuation of a light beam in the semiconductor is described by the Lambert-Beer's law:

$$\phi(x) = \phi_0 \cdot e^{-\alpha x}$$

# Charged particles

- Charged particles continuously interact with electrons and protons in the nucleus via the long-range Coulomb force.
- Most interactions are elastic (Rutherford) scattering with atomic electrons.
- The basic theory has been developed by Bohr using classical arguments, and later in a quantum mechanical way by Bethe (1930), Bloch (1933) and Landau (1944).
- Since the time that the electrostatic force acts on the electron is inversely proportional to the velocity, the energy loss is inversely proportional to the square of the particle velocity.
- Minimum Ionizing Particle Energy Loss in Si: 3.87 MeV/cm.
- Ionizing Energy for e-h pair creation = 3.62eV

## Problem: Getting a Signal from “pure” Silicon



### Intrinsic semiconductor:

Pure (undoped) semiconductor the electron density  $n$  and hole density  $p$  are equal.

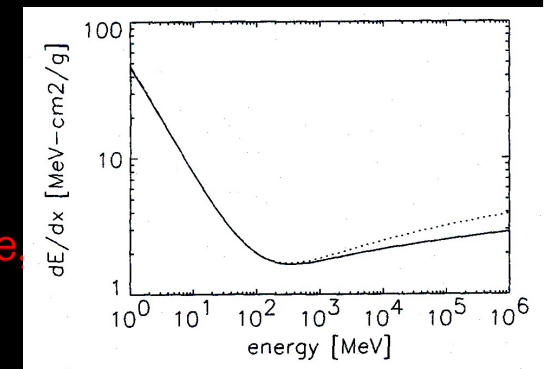
$$n = p = n_i$$

For Silicon:  $n_i \approx 1.45 \cdot 10^{10} \text{ cm}^{-3}$

### Signal generated by an Ionizing particle passing through 300 μm intrinsic Silicon

- Ionization energy  $I_0 = 3.62 \text{ eV}$ ,
- mean energy loss for a mip  $dE/dx = 3.87 \text{ MeV/cm}$   $\longrightarrow$   
 $[dE/dx \times d] / I_0 = [3.87 \times 0.03] / 3.62 = 3.2 \times 10^4 \text{ e-h pairs}$

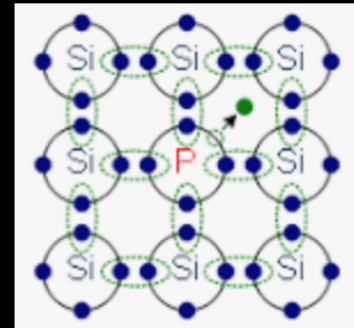
➤  $4.5 \cdot 10^8$  free charge carriers in  $1 \text{ cm} \times 1 \text{ cm} \times 300 \mu\text{m}$  volume,  
 but only  $3.2 \cdot 10^4$  e-h pairs produced by a M.I.P.



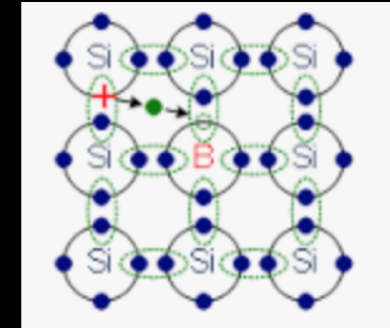
- Need to reduce number of free carriers, hence deplete the detector
- Solution: Make use of reverse biased p-n junction (reverse biased diode)!!

# Doping and p-n Junction

- Doping: n-type Silicon
  - add elements from V<sup>th</sup> group  
□ donors (P, As,..)
  - electrons are majority carriers
- Doping: p-type Silicon
  - add elements from III<sup>rd</sup> group  
□ acceptors (B,..)
  - holes are majority carriers



The P atom donated its 5<sup>th</sup> valence electron which becomes a free charge carrier



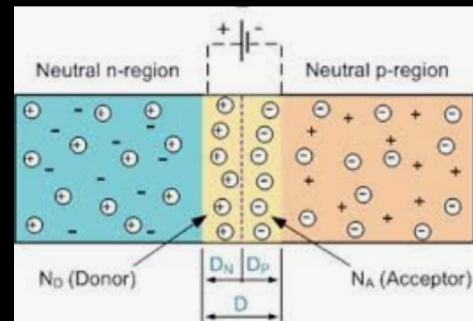
A free place in a B atom is filled with an electron therefore a new hole is generated

	detector grade	electronics grade
<b>doping</b>	$\approx 10^{12} \text{ cm}^{-3}$	$\approx 10^{17} \text{ cm}^{-3}$
<b>resistivity <math>\rho</math></b>	$\approx 5 \text{ k}\Omega \text{ cm}$	$\approx 1 \text{ }\Omega \text{ cm}$

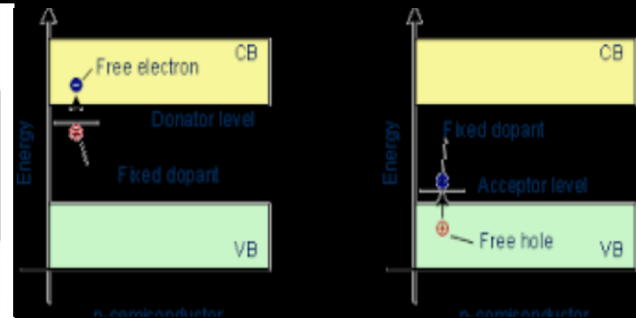
## Resistivity

- carrier concentrations  $n, p$
- carrier mobility  $\mu_n, \mu_p$

$$\rho = \frac{1}{q_0} (\mu_n n + \mu_p p)$$



## p-n junction

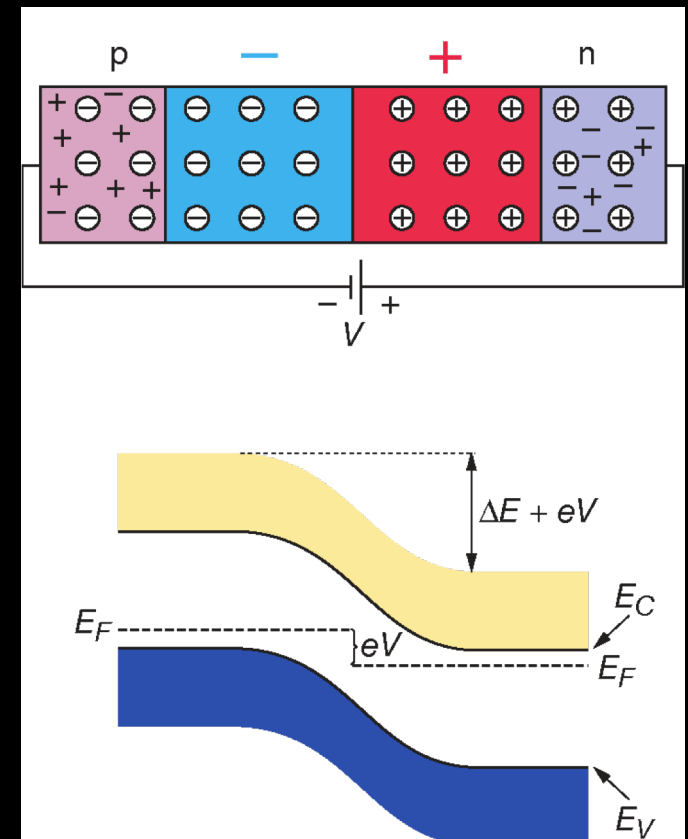


## The depletion region

- At the interface of an n-type and p-type semiconductor the difference in the Fermi Levels ( $E_F$ ) which is the energy level with a 50% probability of being occupied by an electron at any given time cause diffusion of surplus carries to the other material until **thermal equilibrium** is reached. At this point the fermi level is equal. The remaining ions create a space charge and an electric field stopping further diffusion.
- Operation with reverse bias**
  - applying an external voltage  $V$  with the cathode to p and the anode to n
  - e and h are pulled out of the depletion zone. The depletion zone becomes larger.
  - The potential barrier becomes higher and diffusion across the junction is suppressed. The current across the junction is very small "**leakage current**".

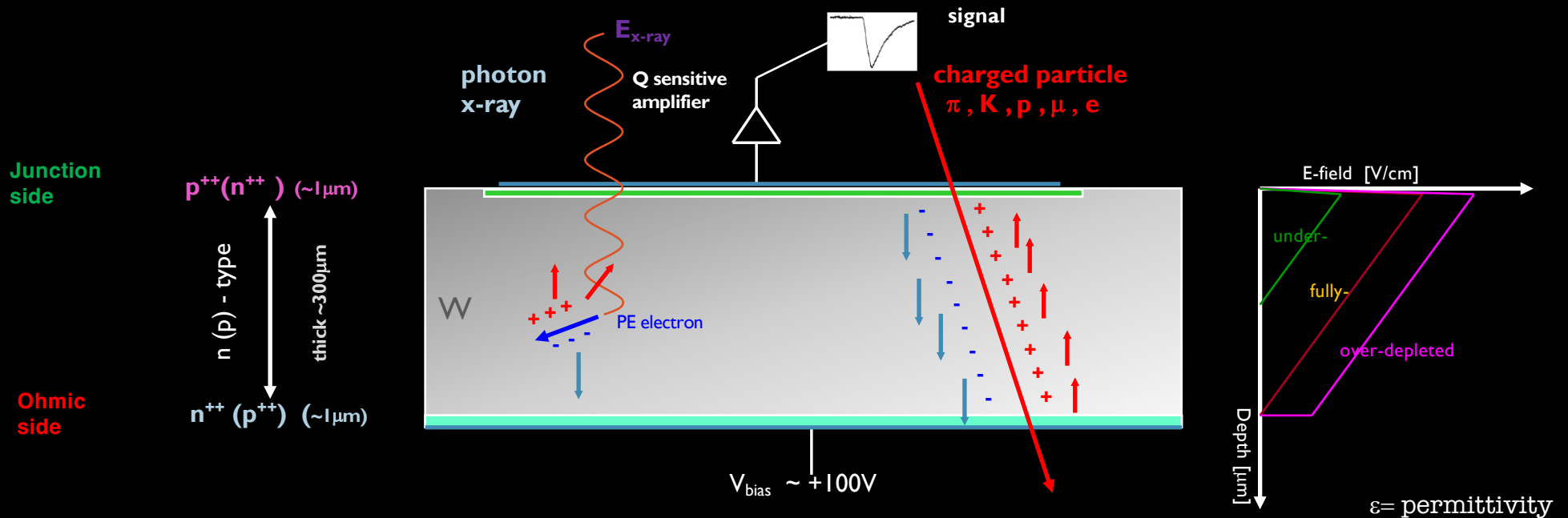
**Et voilà, that's the way we operate our semiconductor detectors!**

p-n junction with reverse bias





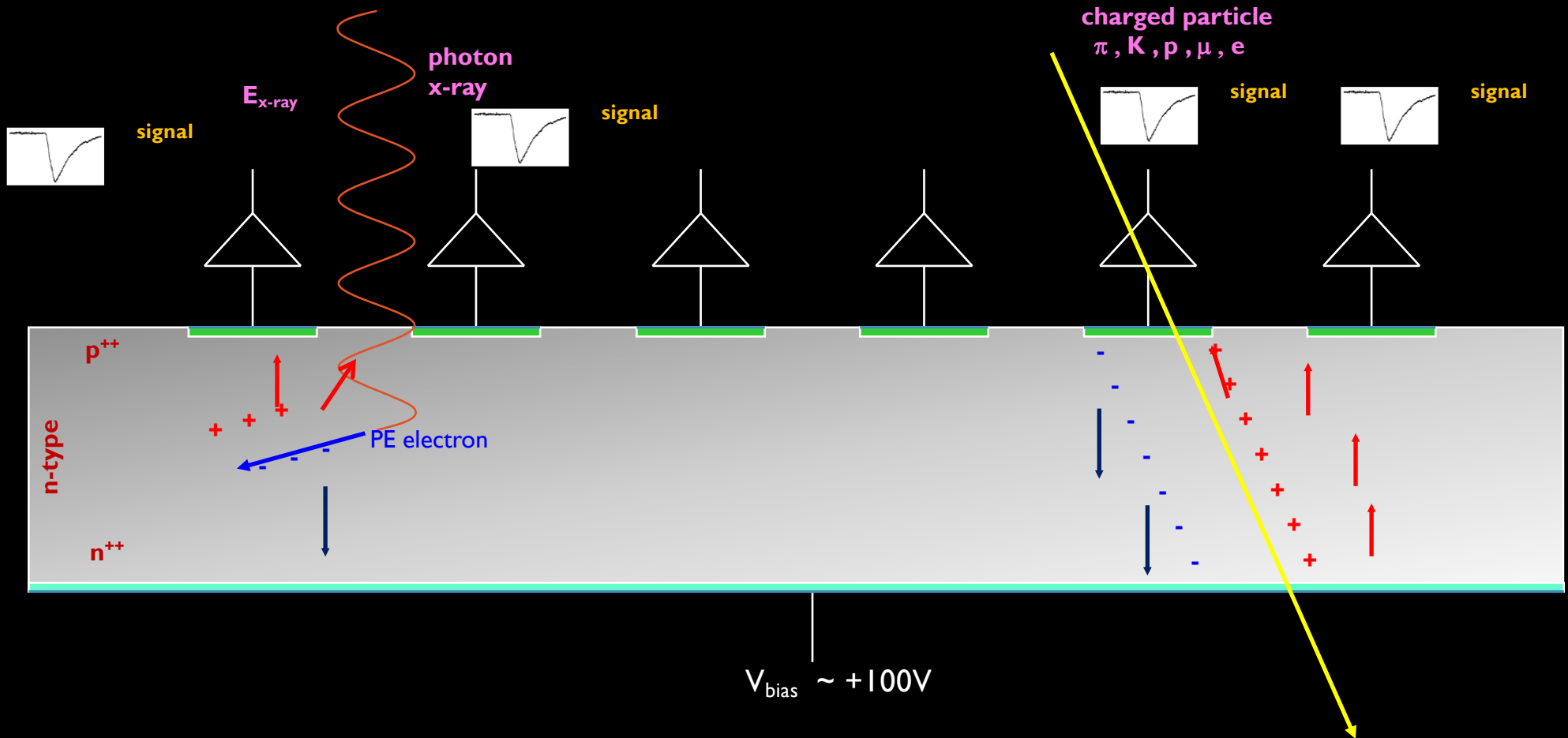
# p-n junction detector basic working principle



- ❖ n<sup>+</sup> and p<sup>+</sup> electrodes are implanted on the wafer's surfaces to form a p-i-n junction
- ❖ V<sub>bias</sub> is the applied reverse bias voltage, W is the depletion region
- ❖ e-h pairs are created by the energy released by the impinging particle
- ❖ e-h drift towards the positive and negative electrode "inducing" a current pulse
- ❖ Charge collection time depends on the carrier mobility, bias voltage and carrier polarity

$$V_{\text{bias}} = \frac{(W)^2 \times e \times |N_{\text{eff}}|}{2\epsilon_0 \epsilon_{\text{Si}}}$$

# Segmented Silicon Sensors for better position sensitivity ..“imaging”



# Leakage Current

$$I_D = I_S (e^{qV_D/NkT} - 1)$$

## • Generation Current:

From "thermal" generation in the depleted region

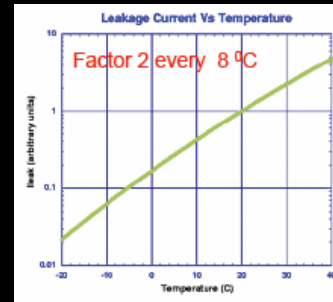
$$j_{gen} \propto T^{3/2} \exp\left(\frac{1}{2kT}\right)$$

It's minimal if the bulk is high resistivity and with low impurities

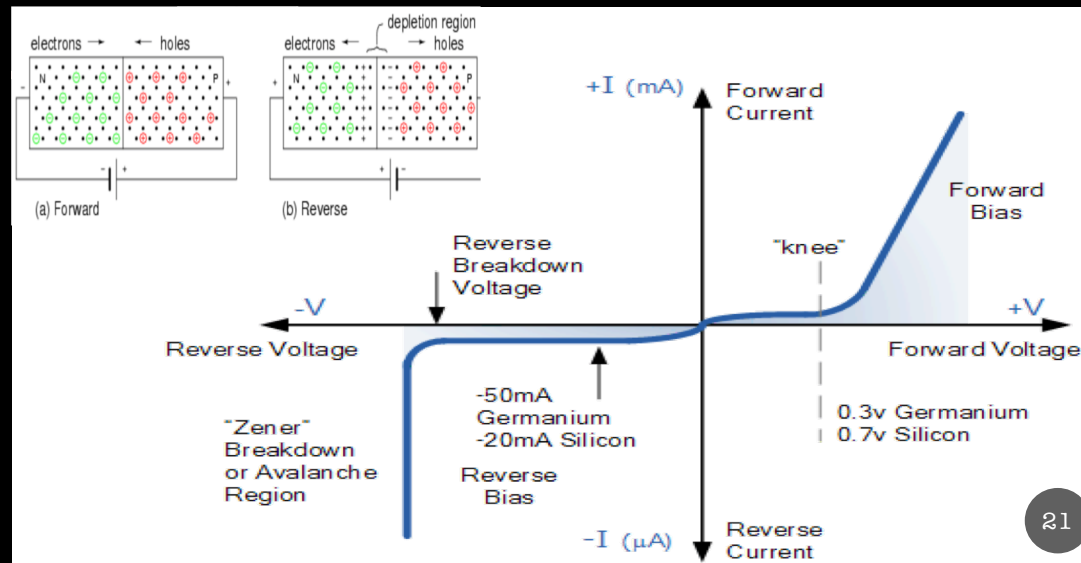
## • Diffusion Current:

Carriers from the 'un-depleted' region  
Diffusing into the depleted region

Doubles every 8°C



- $I_D$  = Diode current in amps
- $I_S$  = Saturation current in amps (typically  $1 \times 10^{-12}$  amps)
- $e$  = Euler's constant ( $\sim 2.718281828$ )
- $q$  = charge of electron ( $1.6 \times 10^{-19}$  coulombs)
- $V_D$  = Voltage applied across diode in volts
- $N$  = "Nonideality" or "emission" coefficient (typically between 1 and 2)
- $k$  = Boltzmann's constant ( $1.38 \times 10^{-23}$ )
- $T$  = Junction temperature in Kelvins



# Signal to Noise and Landau distribution

## SIGNAL if there is a PARTICLE

- Signal formed no matter what
- Detection efficiency

## NO SIGNAL if NO PARTICLE

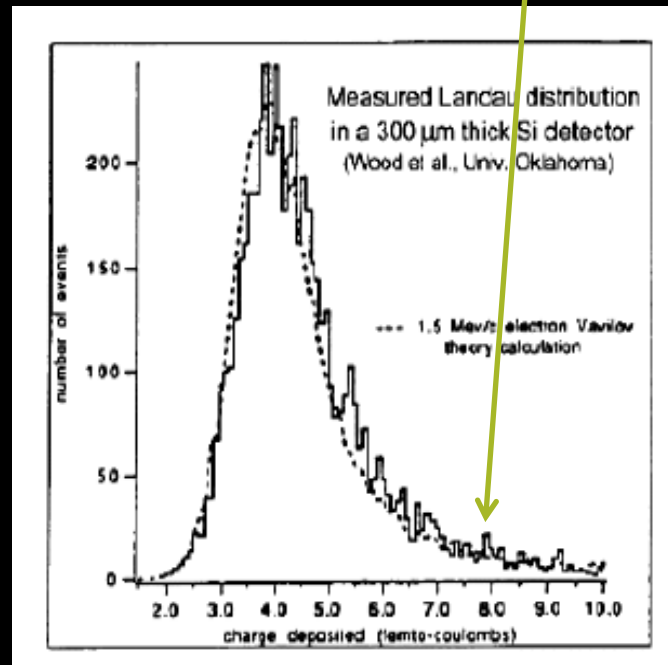
- Noise under control
- Discrimination

Mean  $(dE/dx)$  Si = 3.88 MeV/cm  
 $\Rightarrow$  116 keV for 300  $\mu\text{m}$  thick Si ( $\sim 75e/\mu\text{m}$ )

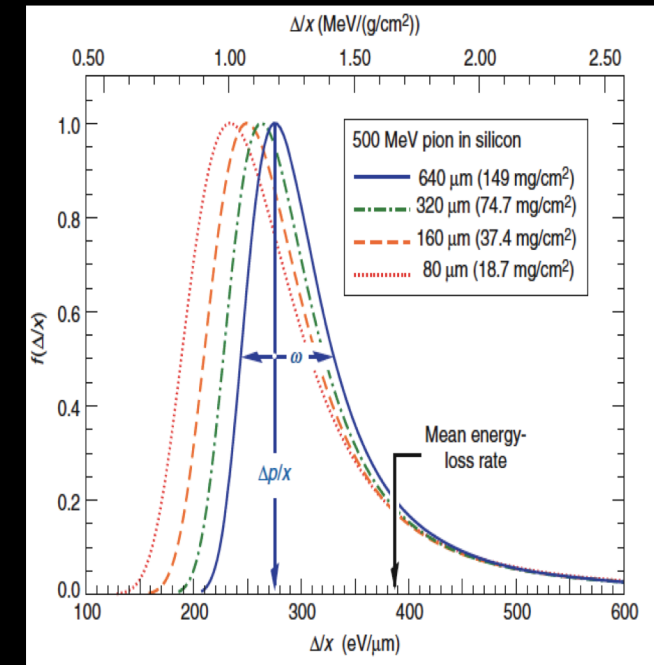
Most probable loss = 81 keV for 300  $\mu\text{m}$  Si  
 Since 3.6 eV needed to make e-h pair  
 $\Rightarrow$  charge in 300  $\mu\text{m}$  = 22500  $e^-$  (=3.6 fC)  
 (75e/ $\mu\text{m}$ )

Mean charge = Most probable charge  $\approx 0.7 \times$   
 mean

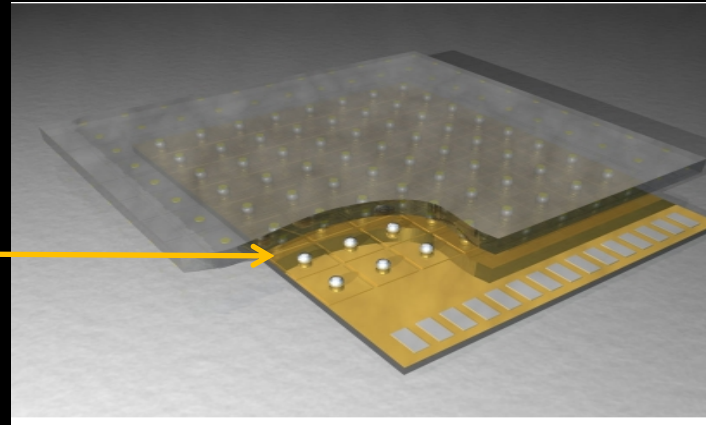
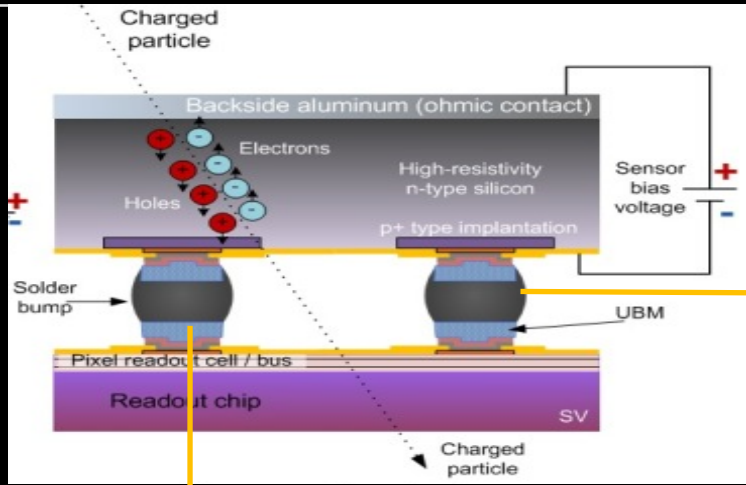
High energy tail  
 From delta rays



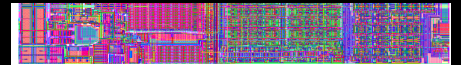
Width depends on  
 Substrate thickness



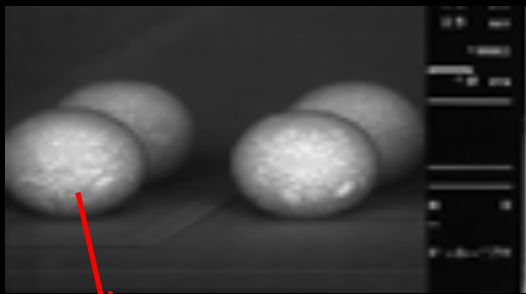
# Two-dimensional segmentation. Pixel Detectors "Hybrid"



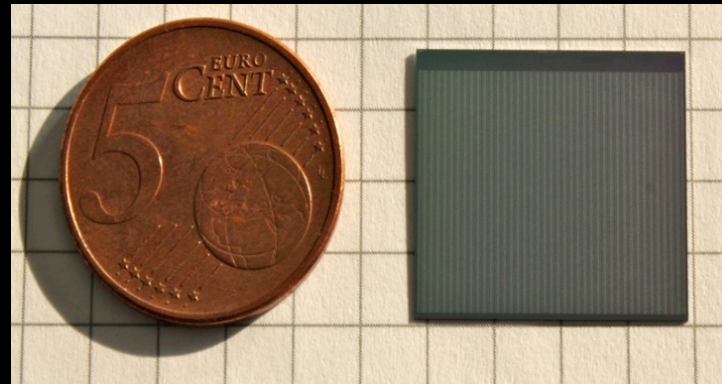
FE-I4  
80x336  
=26 880 pixels  
125 x 50  $\mu\text{m}^2$



solder



50 microns (25 $\mu\text{m}$  In, <10 $\mu\text{m}$  Au)



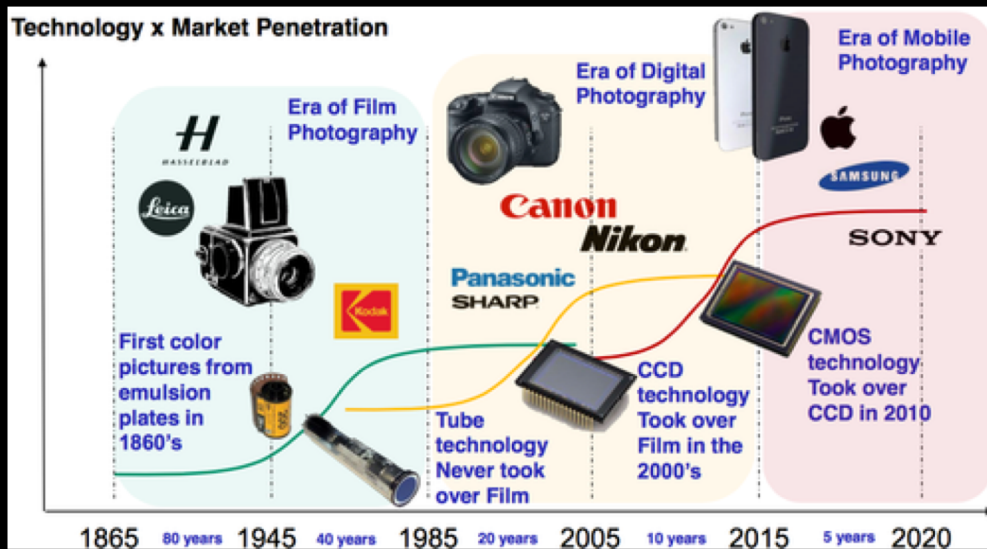
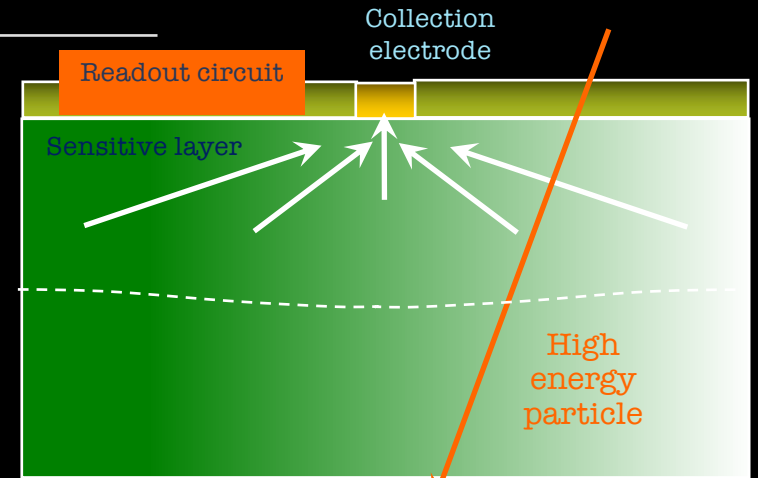
ATLAS FE-I4 ~4 $\text{cm}^2$

# Pixel detectors “Monolithic”

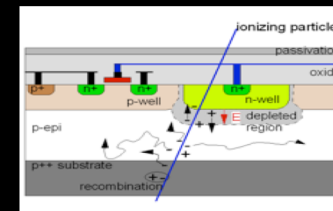
Integrate the readout circuitry together with the detector in ‘one piece’ of silicon

The charge generated by a particle is collected on a defined collection electrode either by diffusion or by the application of an E-field

Small pixel size and thin effective detection thickness

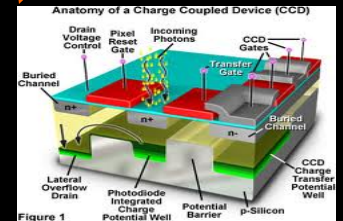


MAPS



Pixel size :  
20 x 20 micron  
Thickness  
20-50 um

Used in the  
EUDET telescope And at  
STAR at RICH



CCD  
Charge coupled  
Device  
Various  
dimensions

Many uses in  
Different fields

# Pixels detectors

Hybrid

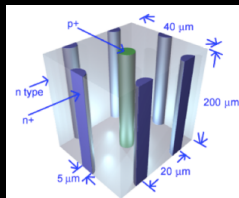
Radiation Hardness



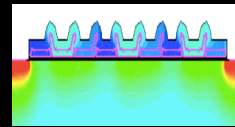
Granularity, low mass

Monolithic

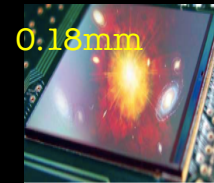
3D sensors



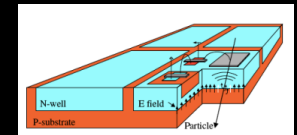
CCD



Mimosa



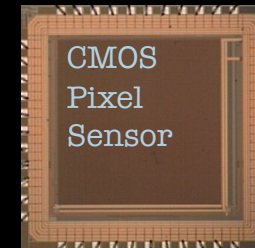
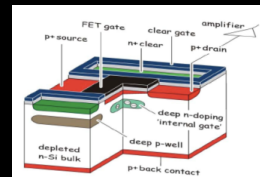
HV-MAPS



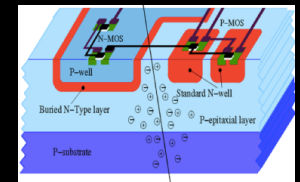
diamond



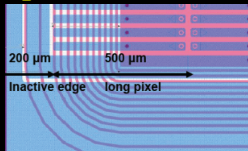
DEPFET



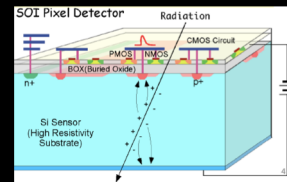
deepNwell



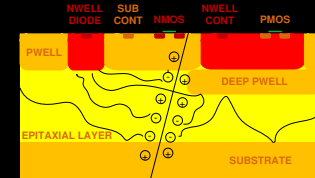
n-in-n, n-in-p-  
planar



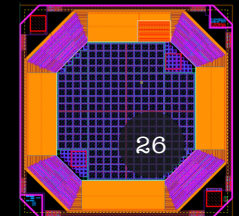
SOI



INMAPS



LePiX



# ALICE ITS3: a bent stitched MAPS-based vertex detector



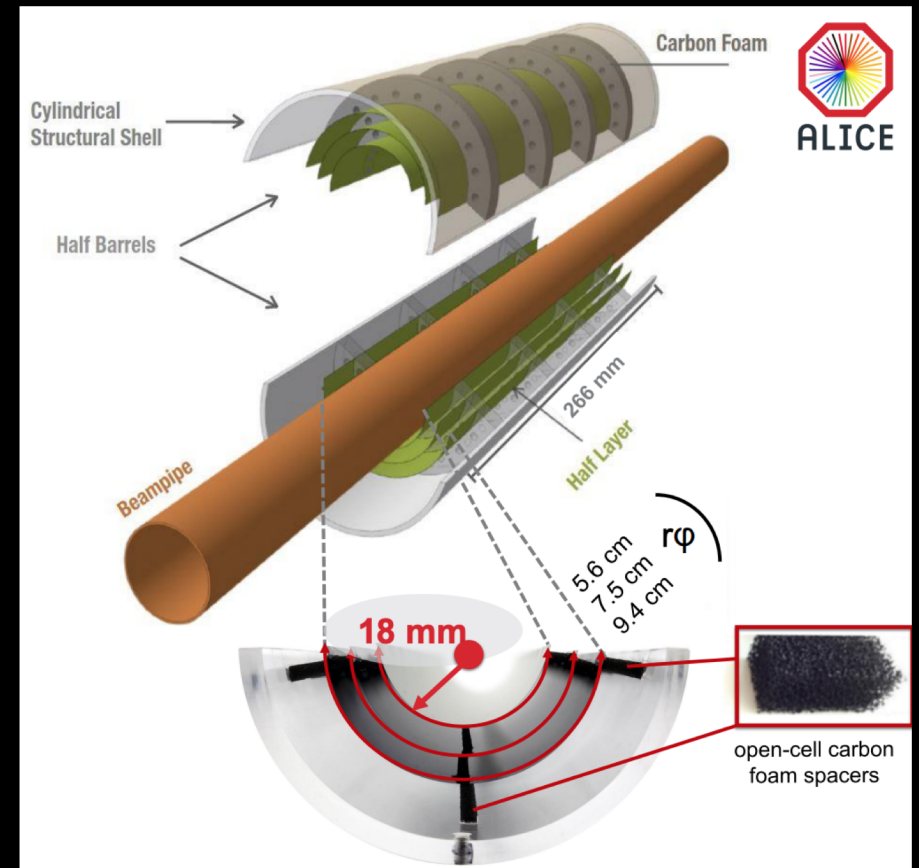
## Using special properties of silicon

- Wafer-scale sensor ASICs - Fabricated with stitching
- All electrical signals and power routed on-chip
- **Ultra-thin and bendable: 50  $\mu\text{m}$**
- 266 mm (Z) x variable width\* ( $r\phi$ )
- CMOS MAPS • 65 nm technology
- Open-cell carbon foam spacers

## Key benefits

- Extremely lightweight
  - Material budget: 0.35%  $X_0^*$  => 0.05%  $X_0$
- Uniformly distributed material
- Closer to interaction point
  - Beam pipe radius: 18.2 mm => 16 mm
  - Radial position: 24 mm => 18 mm

\* $X_0$  (radiation length)=the mean length (in cm) into the material at which the energy of an electron is reduced by the factor  $1/e$

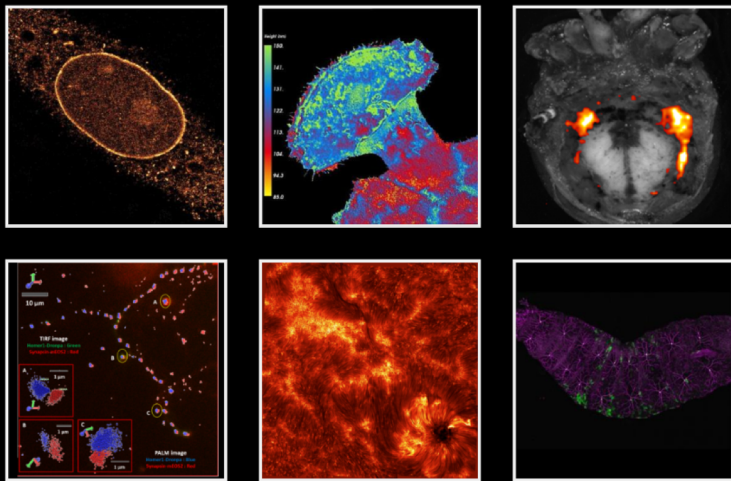


Slide from From Ola Groettvik

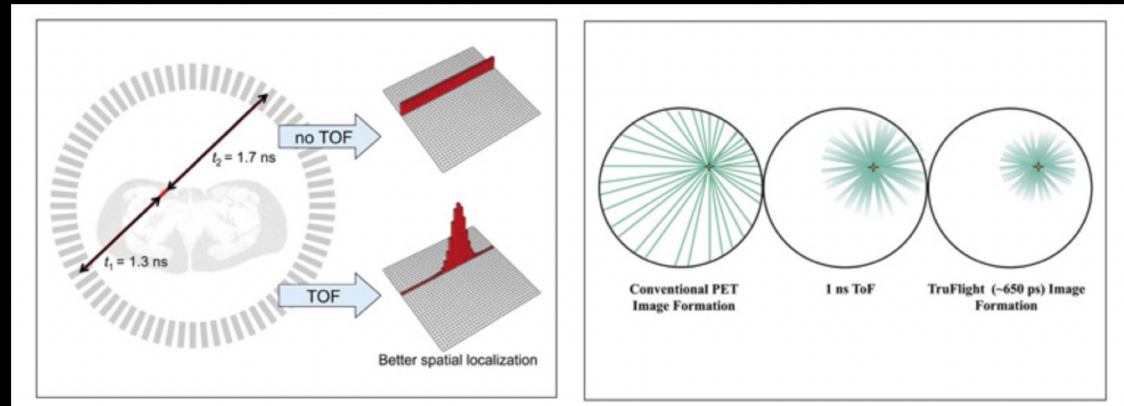
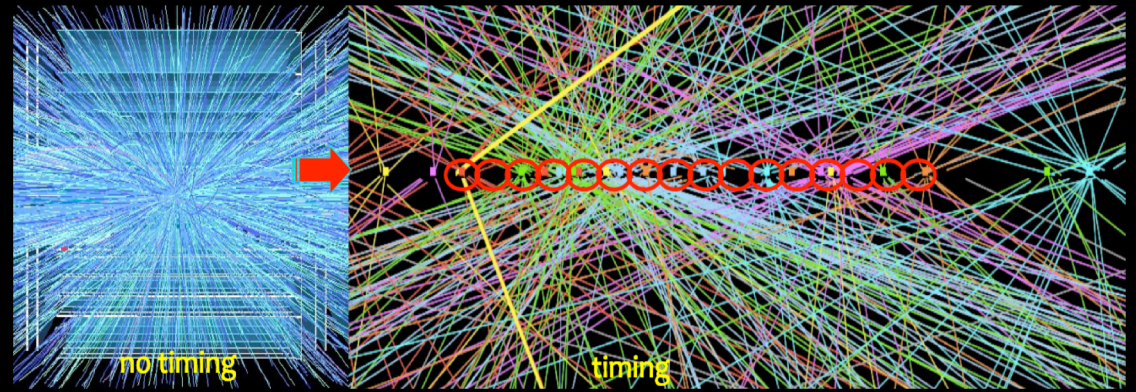


# High Precision Imaging in space and time

## Fundamental Science



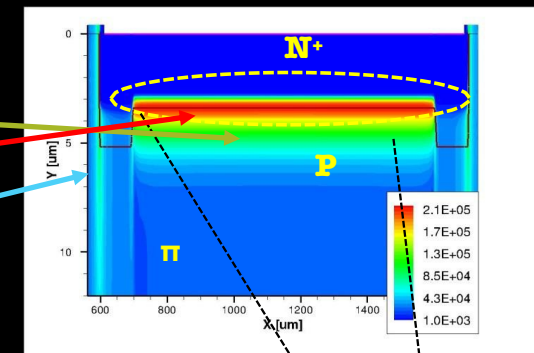
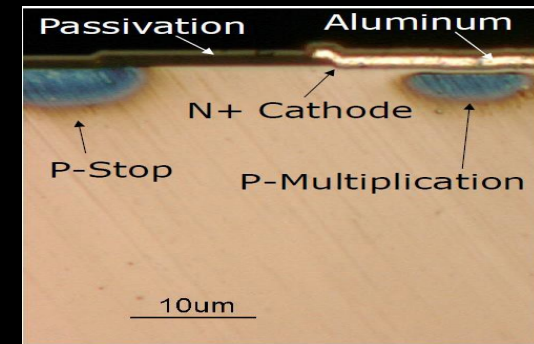
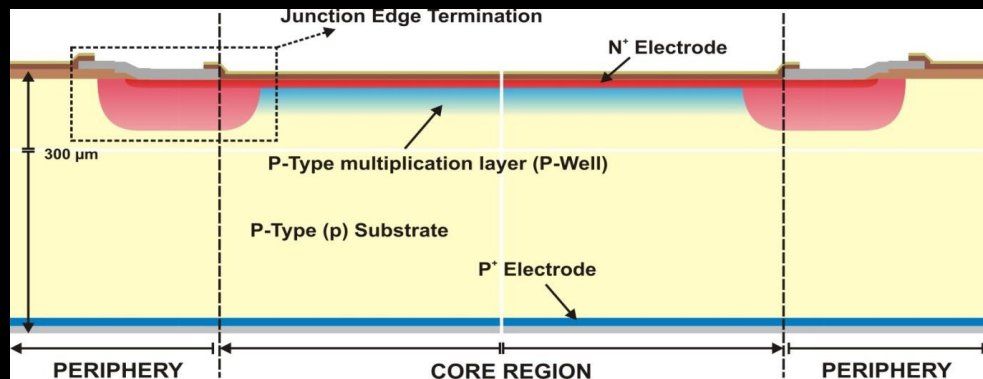
## Biology



## Medical Imaging

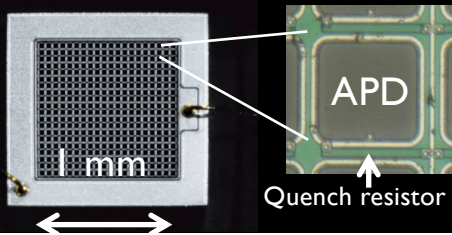
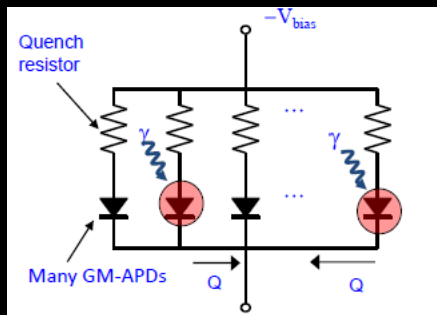
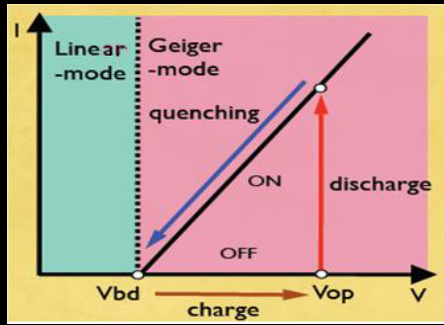
# LGAD Basics. Low Gain Detector

G. Pellegrini, Low Gain Avalanche Detectors

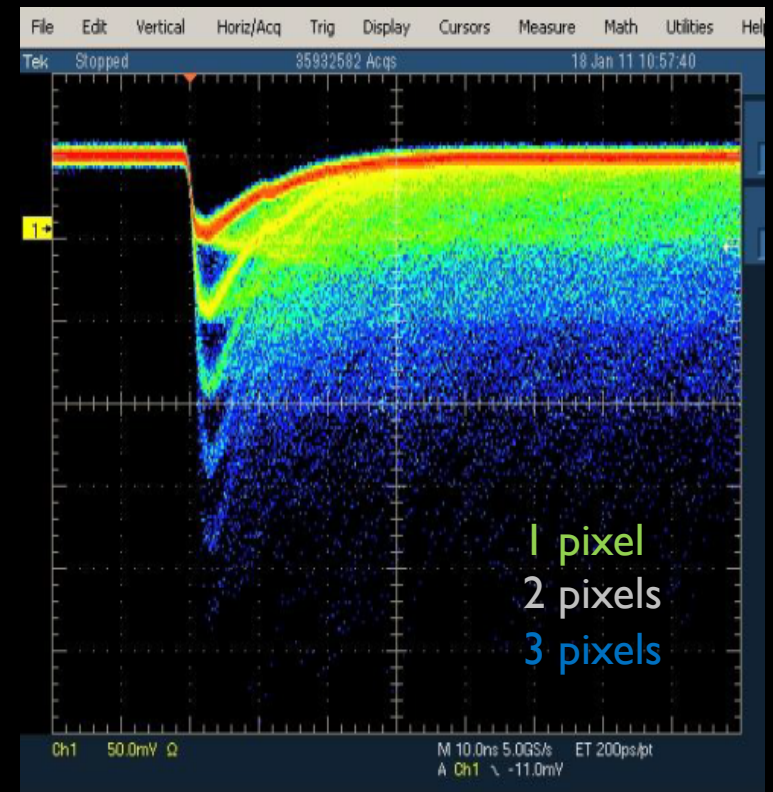


- Core Region
  - ✓ Uniform electric field, high enough to activate mechanism of impact ionization (multiplication)
- Termination
  - ✓ High electric field confined in the core region
- Periphery
  - ✓ Dead region. Charges should not be collected. Reduction of the surface leakage currents

# Silicon Photomultipliers (SiPm)

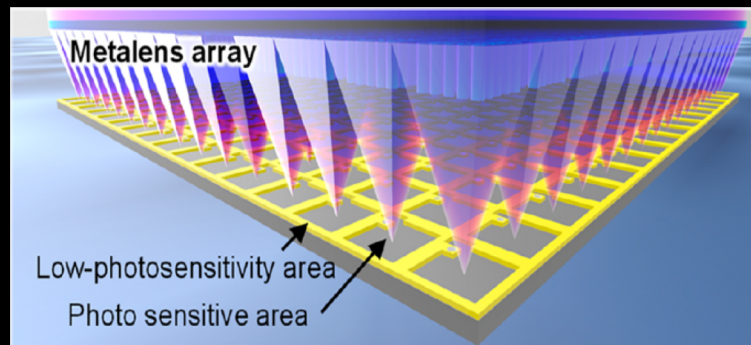


- SiPm requires a special doping profile to allow a high internal field ( $>10^5$  V/cm) which generates avalanche multiplication
- APD cell operates in Geiger mode (= full discharge), however with (passive/active) quenching.
- The avalanche formation is intrinsically very fast (100ps), because confined to a small space.
- High Gain  $G \sim 10^5 - 10^6$  at rel. low bias voltage ( $<100$  V)
- $G$  is Sensitive to temperature and voltage variations
- Fill factor still low due to quench resistor on the surface (but work in progress to solve this)



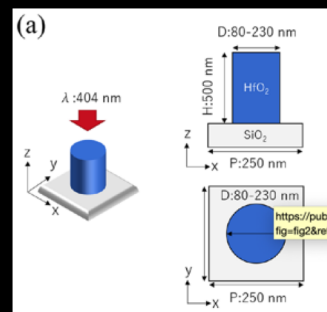
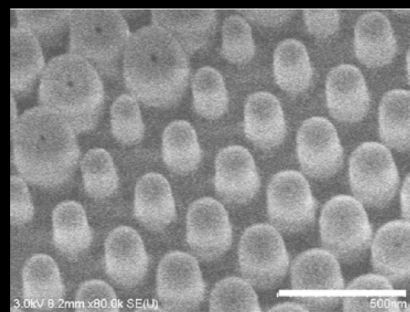
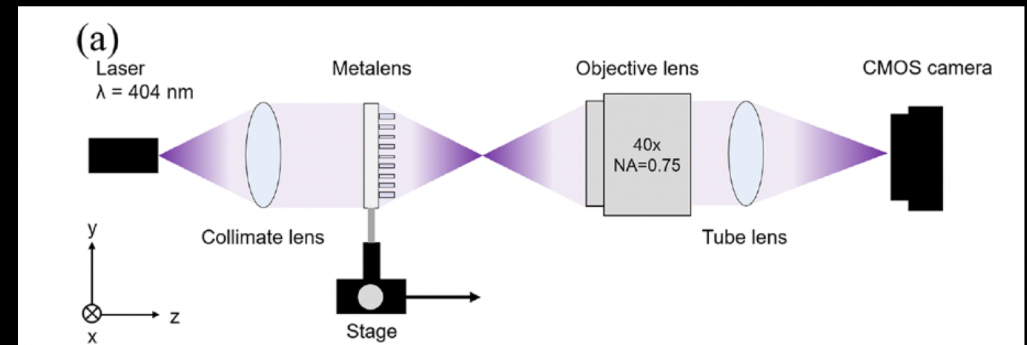
# 40 x 40 Metalens Array for Improved Hamamatsu Silicon Photomultiplier Performance

*Soh Uenoyama\* and Ryosuke Ota ACS Photonics 2021, 8, 1548–1555*

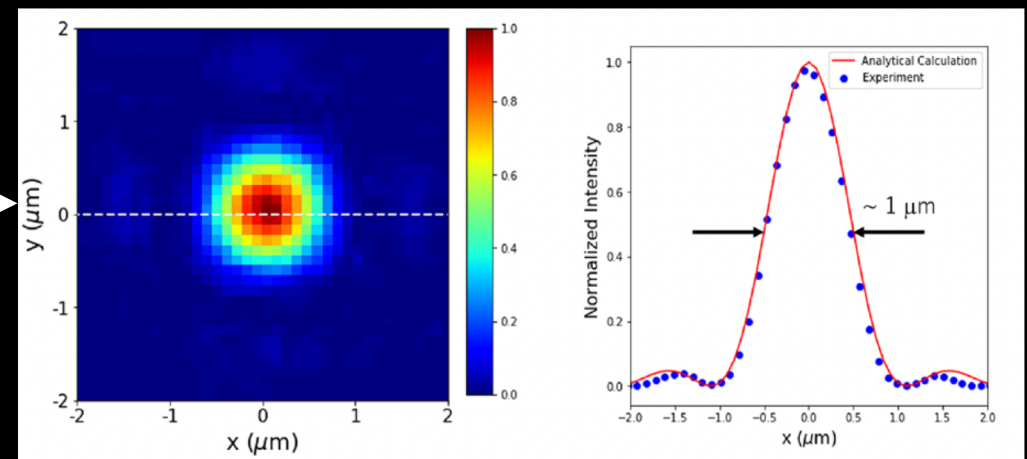


3x3mm<sup>2</sup>  
75μm

~82%  
Fill factor  
(~50%)



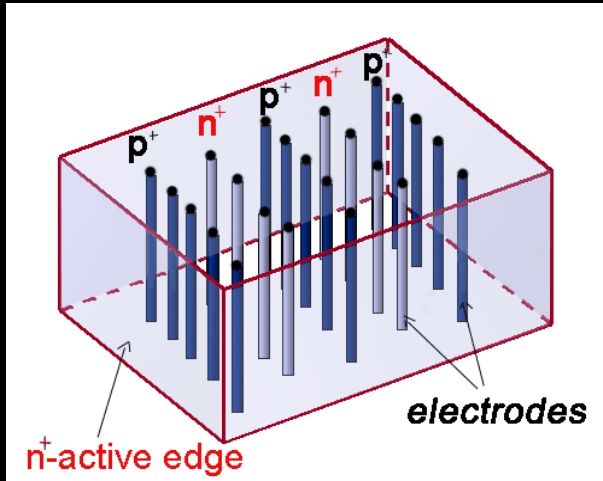
Focal Point  
~ 14.5μm  
Outside focal point



Hafnium oxide (HfO<sub>2</sub>) nanopillars on a 300 μm thick glass substrate to minimise absorption in the Near UV

**circular transmission nanopillar** varies the locally effective index by changing the diameter of the metasurface and does not depend on incident polarization.

# 3D radiation sensors



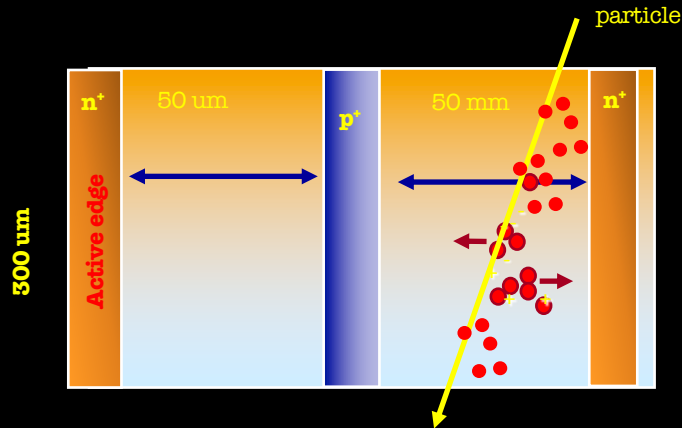
3D silicon detectors were proposed in 1995 by S. Parker, and active edges in 1997 by C. Kenney.

Combine traditional electronics processing and MEMS (Micro Electro Mechanical Systems) technology.

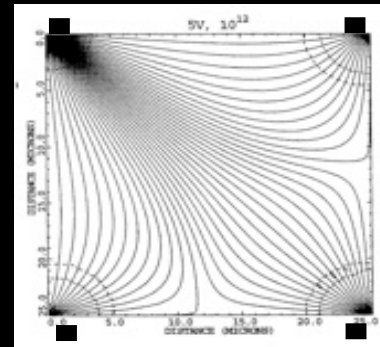
Electrodes are processed inside the detector bulk instead of being implanted on the Wafer's surface.

The edge is an electrode! Dead volume at the Edge < 5 microns!

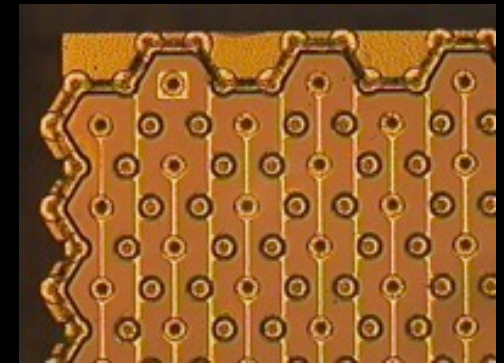
The electric field is parallel to wafer's surface: and smaller inter-electrode spacing: low bias voltage, low power, reduced charge sharing and high speed - for the same wafer thickness



$V = 7V$   
Before irradiation



Drift lines parallel to the surface

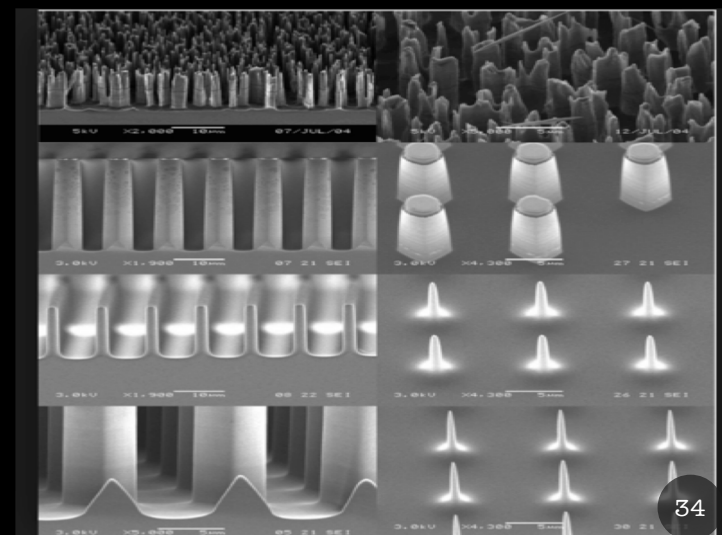
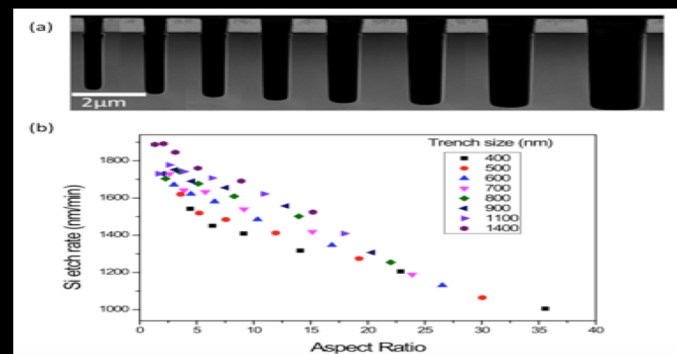
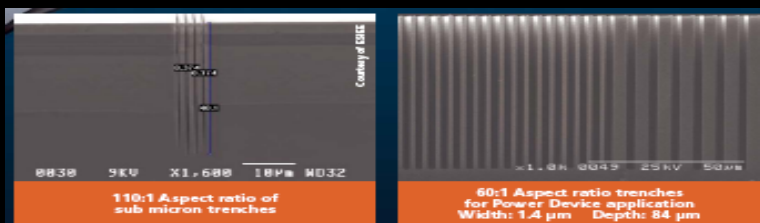
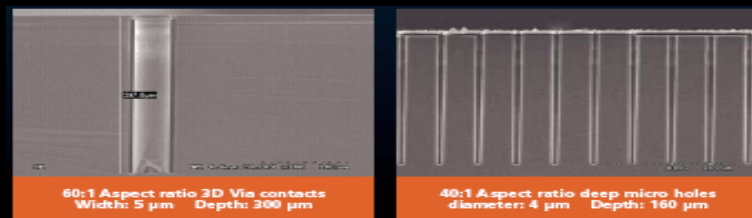
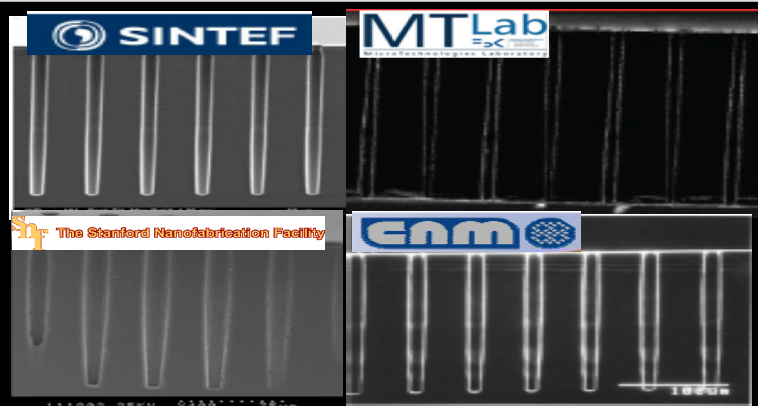


# Precision in space and time Developments in Bulk Micro-Fabrication

NATURE <https://doi.org/10.1038/s41598-020-79560-z>

## Deep Reactive Ion Etching

## Cryo-etching Atomic Level Etching (ALE)

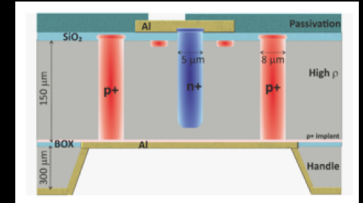


# Fast response and Radiation hardness of 3D sensors

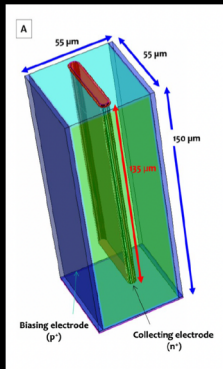
M. Manna et al. NIMA 979 (2020) 164468

A. Lampis 23rd International Workshop on Radiation Imaging Detectors Riva del Garda, June 30th 2022

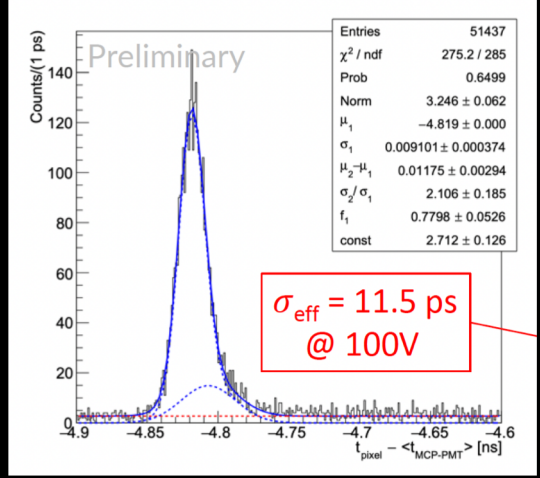
IES  
35um



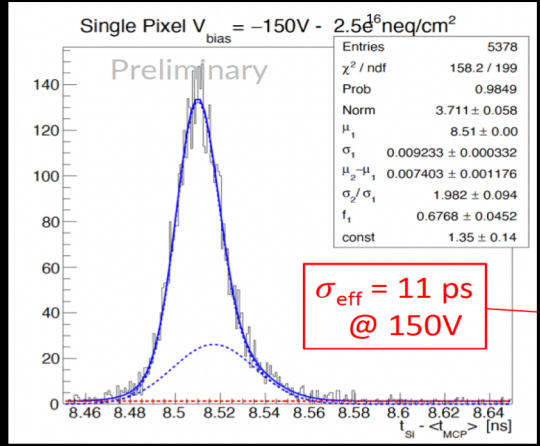
## 3D Trench



180 GeV/c  $\pi^+$  beam

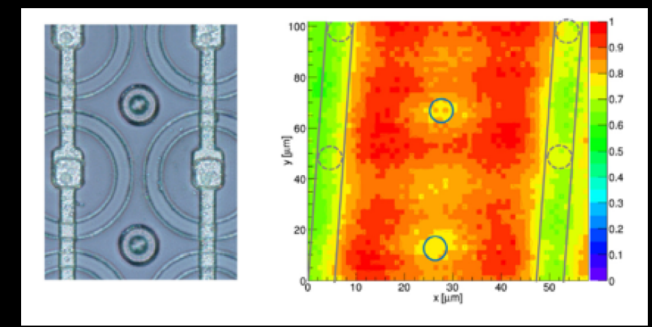
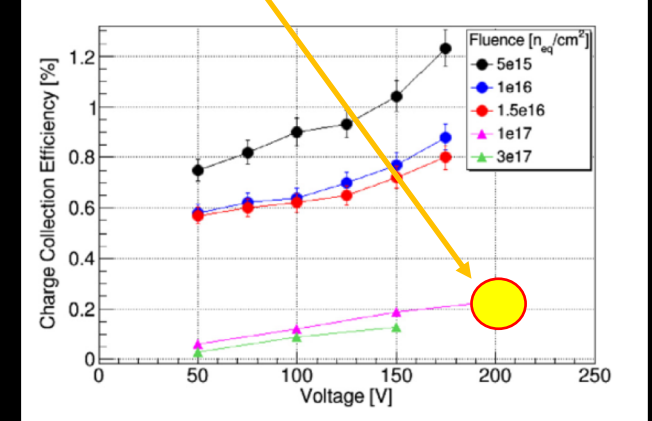


Timing resolution  
Before irradiation



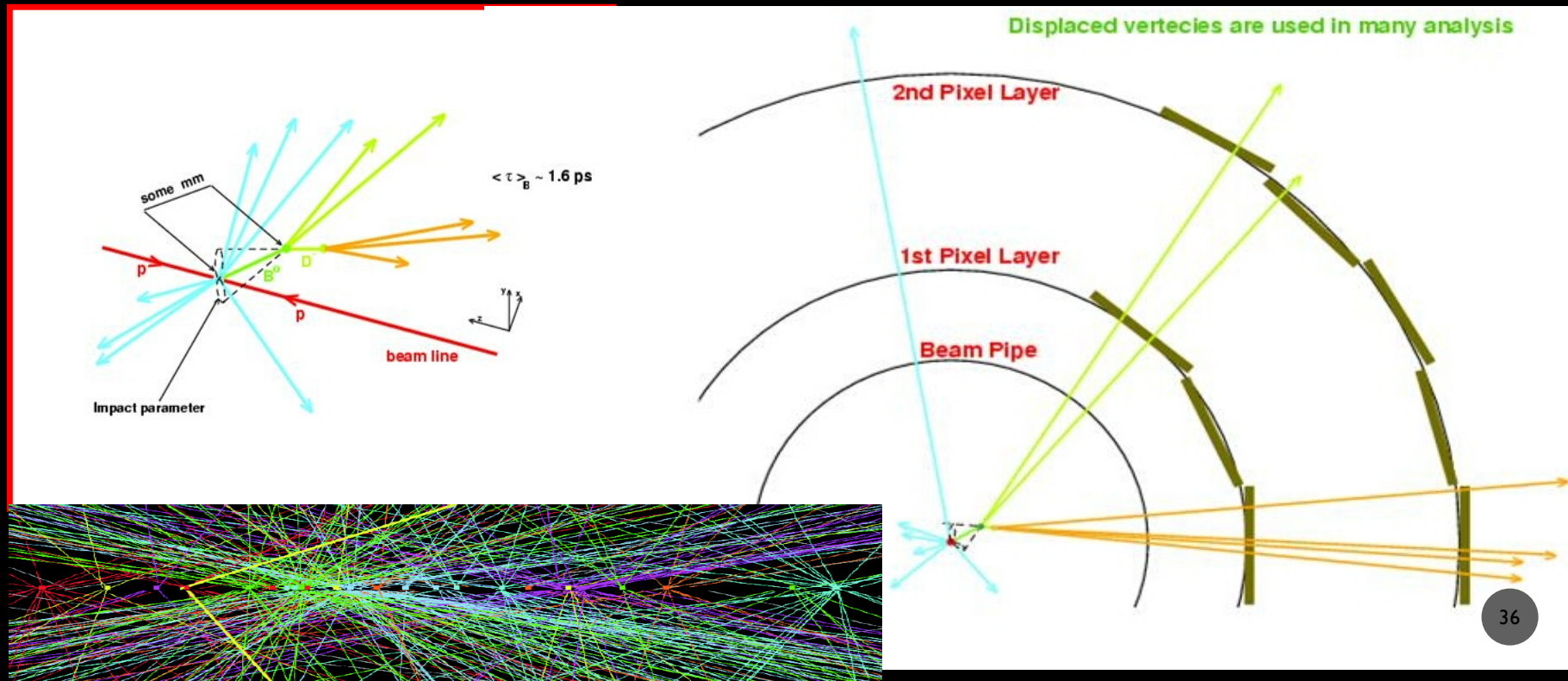
Timing resolution  
after irradiation

$1 \times 10^{17} \text{ neq/cm}^2$  at  
250 V ( $T = -16^\circ\text{C}$ )  
with top IR illumination



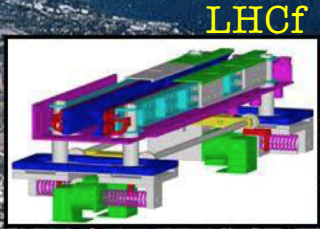
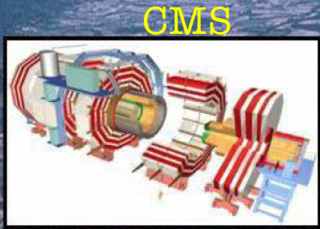
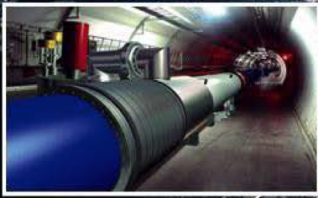
# Example: Tracking Identification of Event Vertices

- primary event vertex reconstruction crucial in multiple collision events
- secondary vertices for live time tagging
- b-jet tagging

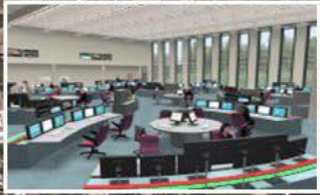




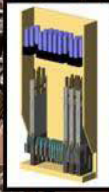
CERN-LHC  
27 Km tunnel  
~100m underground



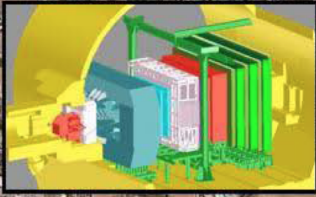
ALICE



ATLAS

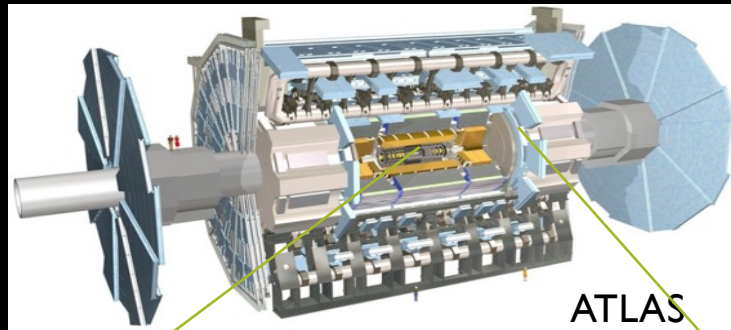


LHCb

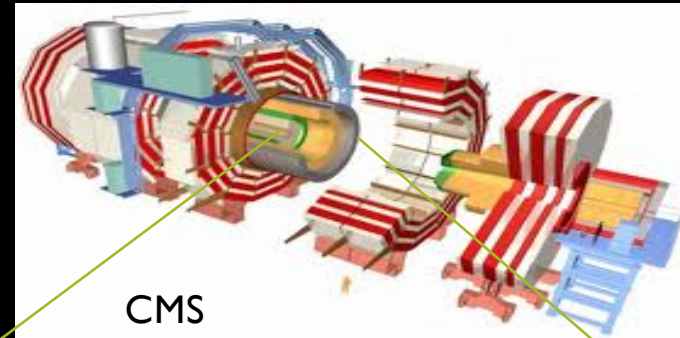


March 2018

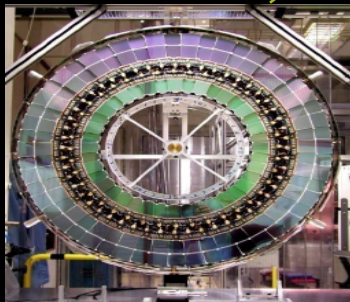
# ATLAS and CMS use alone more than 250m<sup>2</sup> of Silicon Strips to “image” charged particles



ATLAS

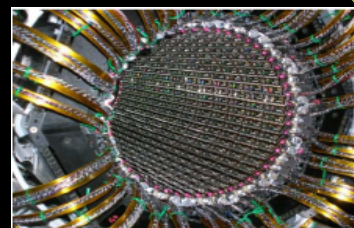


CMS



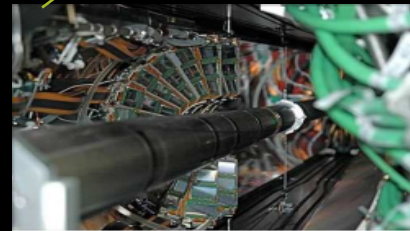
### Strips

61m<sup>2</sup> of silicon.  
6.2million channels 4 barrel  
layers + 9 disks per endcap  
30cm < R < 52cm



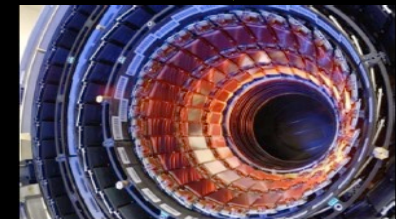
### Pixels

3 Barrel layers  
(r=5,9,12 cm)  
2 end caps each with  
3 disks  
80Mpixels 50x400um<sup>2</sup>  
Digital I/O



### Pixels

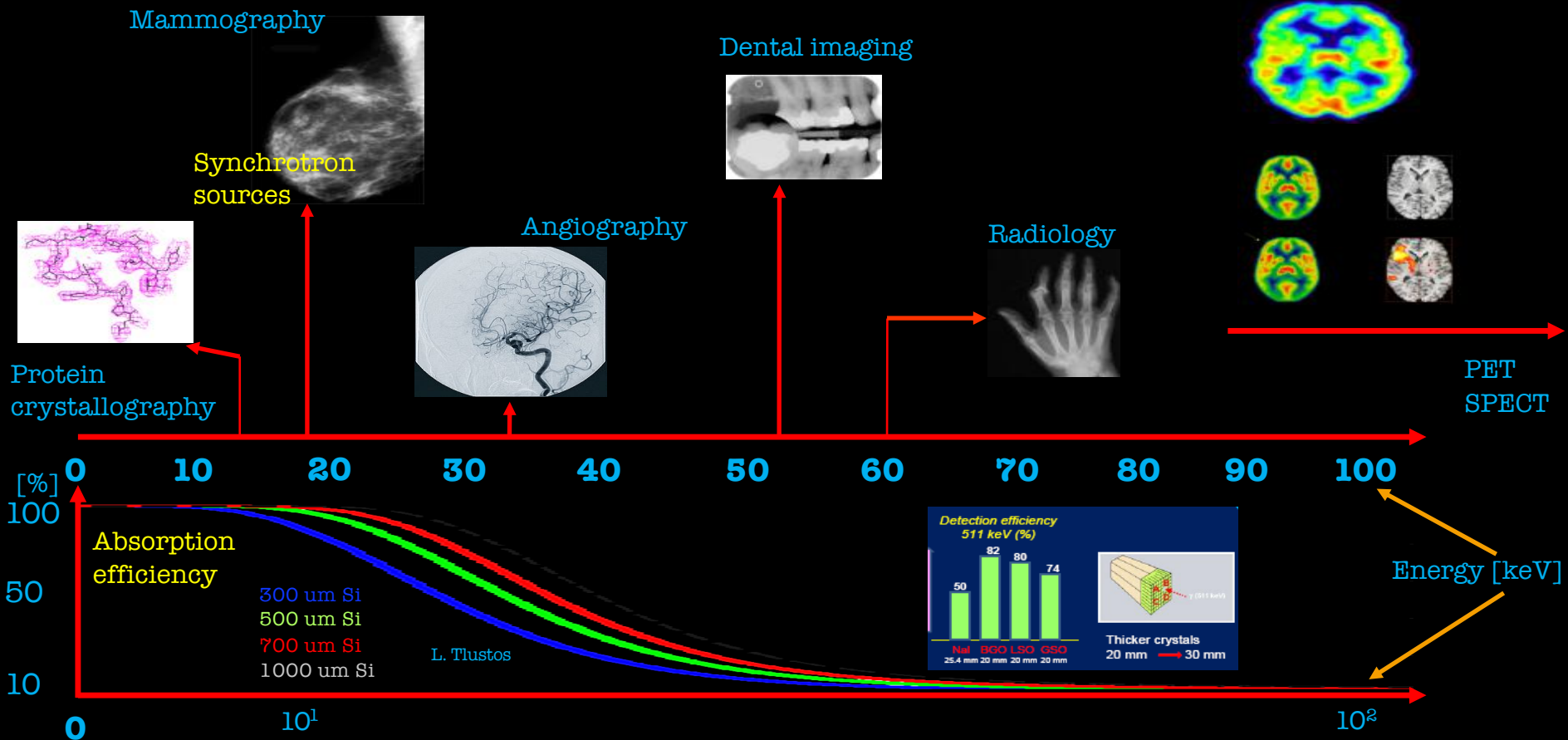
3 barrel layers  
2 end caps each  
with 2 disks  
66 Mpixels 150 x 100um<sup>2</sup>  
Analog I/O



### Strips

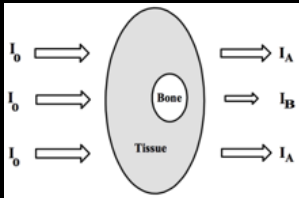
198 m<sup>2</sup> of silicon,  
9.3 million channels  
Inner : 4 barrel layers,  
3 end-cap disks  
Outer: 6 barrel layers,  
9 weels  
22cm < R < 120cm

# X-ray energy of the most common medical and biological applications



# Direct/indirect conversion

**Contrast**



$$I_A/I_B$$

**Resolution  
pixel dimension-x**

**Signal to noise ratio  
S/N**

**Dose to the patient**

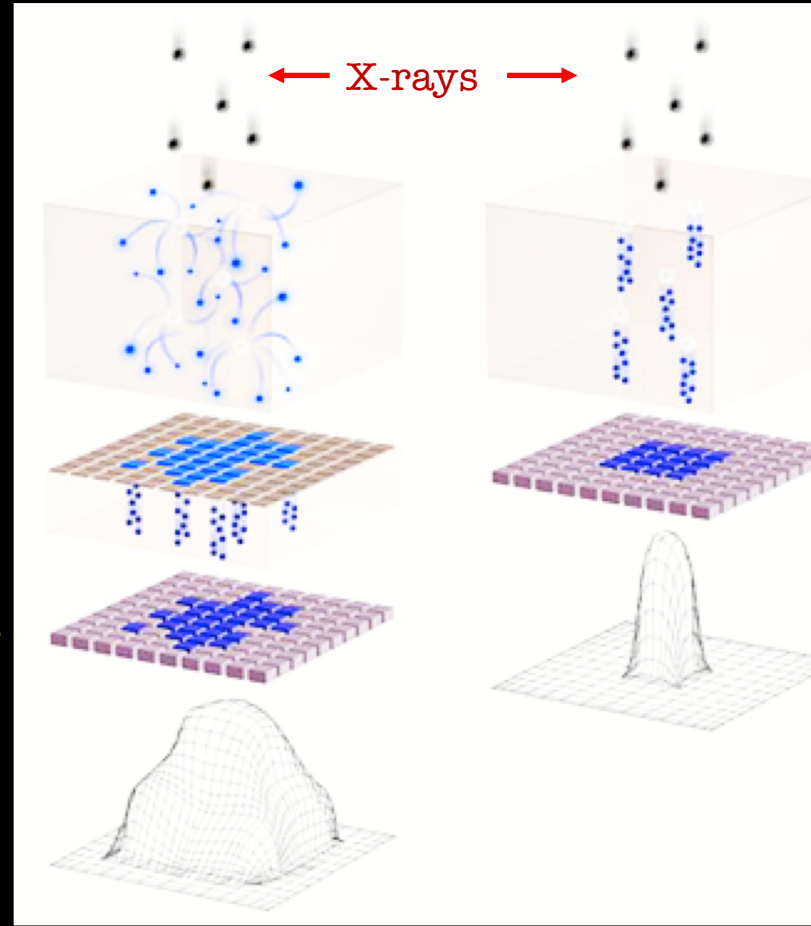
Organ	dose skin mGy	effective dose mSv
Thorax, face	0,2 - 0,5	0,015 - 0,15
Lumbar region	4 - 28	1,5
Urography	40 - 60	3
Brain scan	7 - 78	1
Whole Body scan	30 - 60	4 - 10
Mammography	7 - 25	0,5 - 1

Scintillator  
Gadox, YAG CsI  
(high Z)

Photodiode/ CCD

electronics

Sampled  
image



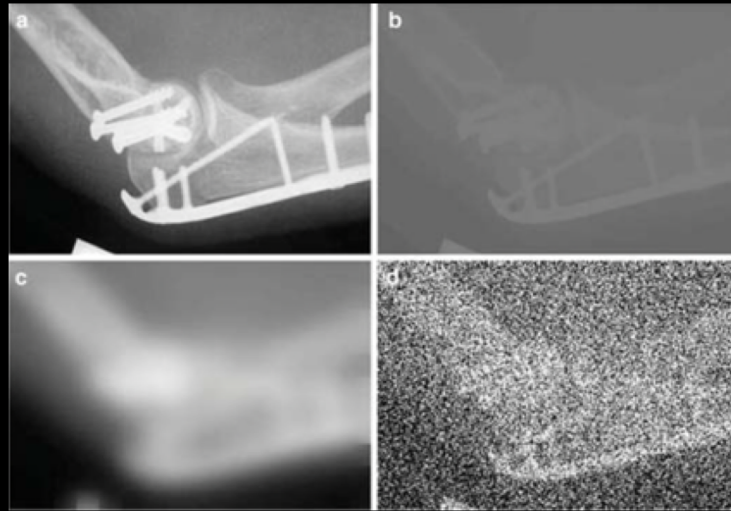
Direct  
conversion  
Si, Ge, CdTe,  
GaAs, Se

electronics

Sampled  
image

# Comparison of different image qualities

*Optimum image quality has adequate resolution and contrast, and a low noise level*

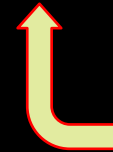


*This image has high spatial resolution and low noise, but it has almost zero contrast.*

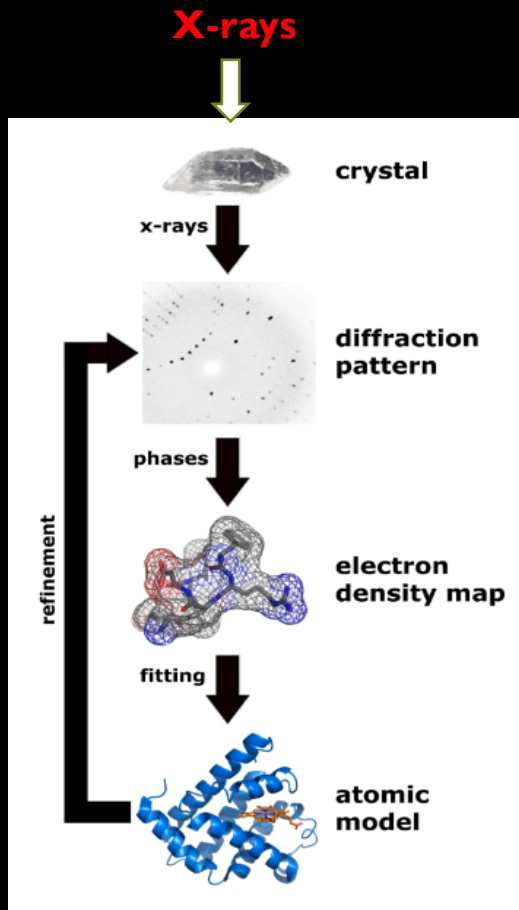
*This image has low noise and high contrast, but very poor spatial resolution.*



*This image has high spatial resolution but very high noise level which destroyed the image contrast*

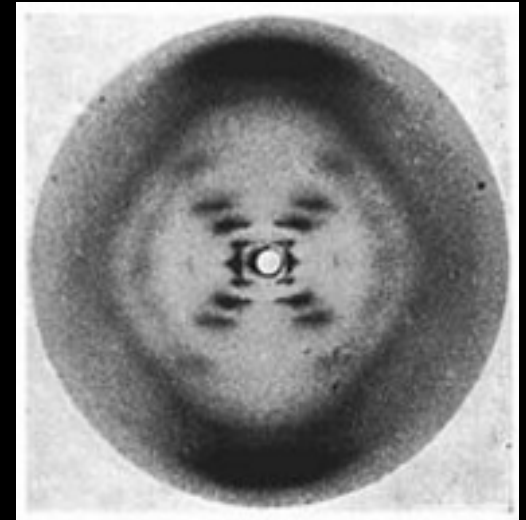
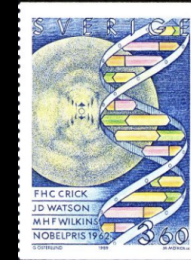
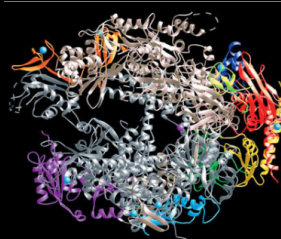
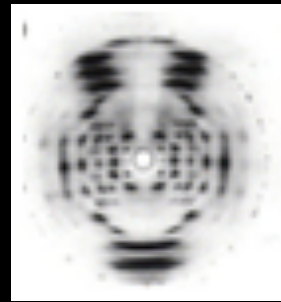
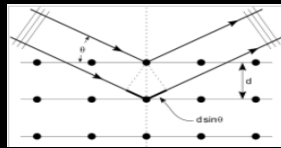
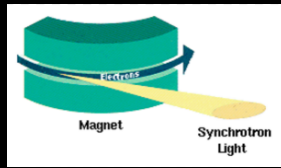


# Synchrotron Radiation: Diffraction Protein crystallography 12 KeV



$$2d \sin \theta = n\lambda$$

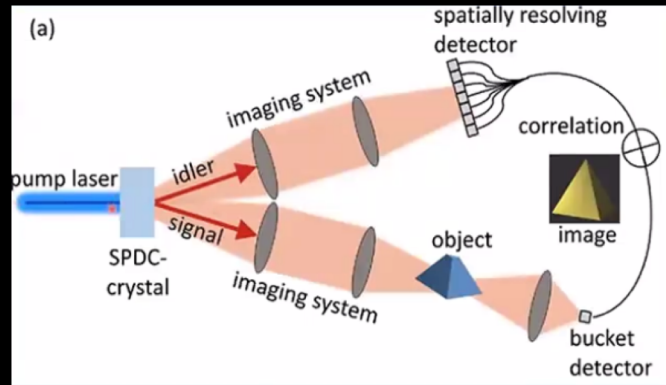
Bragg Law



X-ray diffracted Photographic image of the double helix taken in 1952 by Rosalind Franklin and Raymond Gosling. The DNA sample was fibrous DNA

# Ghost Imaging of undetected photons

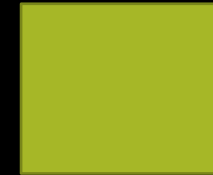
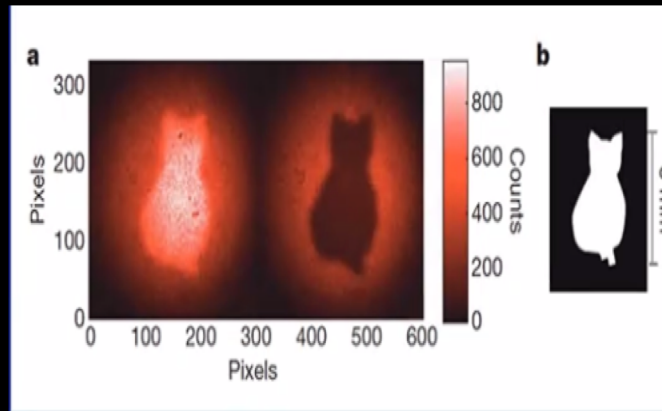
<https://doi.org/10.1364/QJM.2014.QTu1A.1>



Uses Quantum Entanglement – Non-local correlation, superposition states

Entangled Photons generated in Non-Linear medium

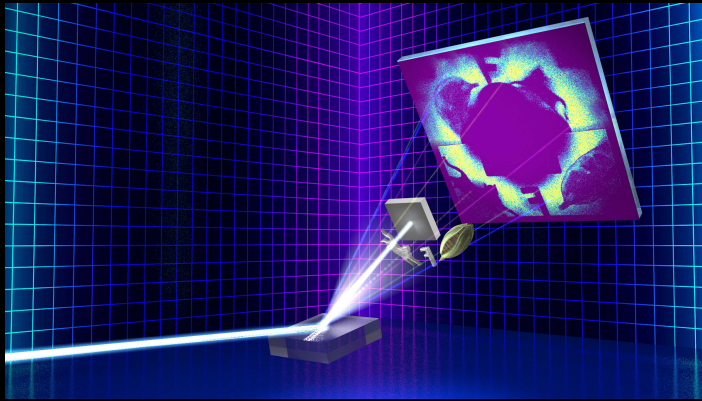
SPDC=Spontaneous Parametric Down Conversion



Bucket detector=No-segmentation placed on the line of the object. Just detects the arrival of a photon, but without position information

# Ghost Imaging with Xrays

Quantum enhanced  
microscope collaboration



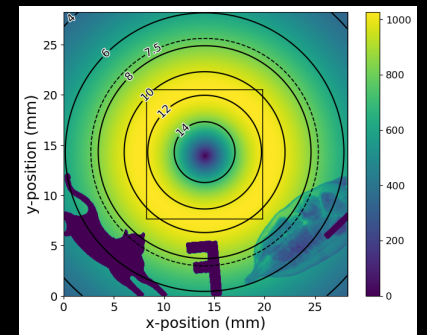
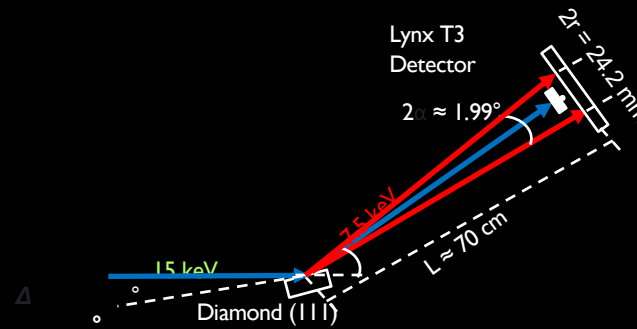
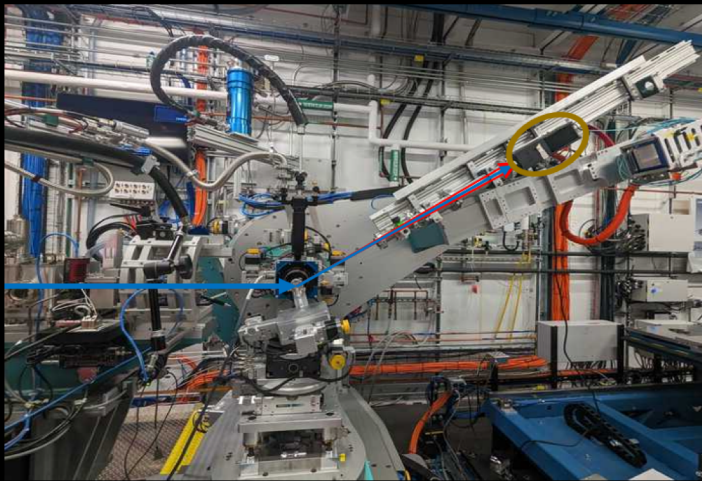
The effect of parametric down conversion (PDC) is the spontaneous decay of a photon of frequency  $\omega_p$  into two of frequencies  $\omega_i$  and  $\omega_s$  in an optically non-linear medium

Energy conservation,

$$\omega_p = \omega_i + \omega_s$$

Momentum conservation

- $k_p = k_i + k_s$





# Environmental Radiation Monitoring

U. Stöhlker

## *Gamma Dose Rate (GDR) networks in Europe*



German Network  
 1800 GDR stations  
 to perform gamma  
 Spectrometry and  
 Create contamination  
 Map for long-lived  
 radionuclides



Inter-calibration facility  
 (INTERCAL) on Schauinsland  
 mountain (1200 m) since 2007

European countries  
 established GDR  
 networks during the  
 cold war period and  
 improved these  
 networks after the  
 Chernobyl accident  
 in 1986.

Monitoring of:  
 nuclear facilities  
 atomic bomb scenarios  
 terroristic attacks

# Detecting Solar Radiation for Energy Harvesting Photovoltaic

A solar cell is basically a p-n-diode where current, voltage and resistance – vary when exposed to light

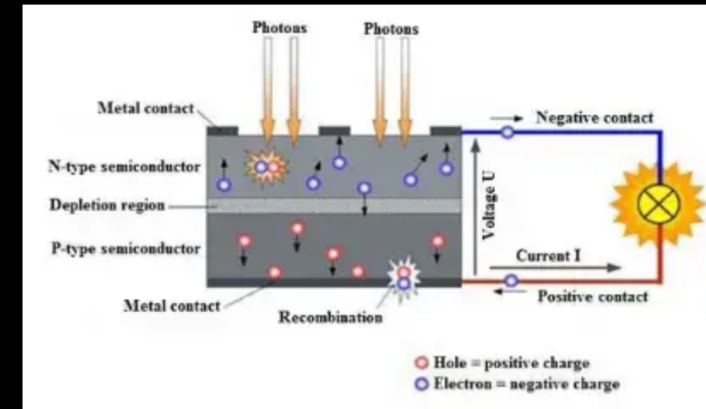
Solar cell Efficiency (Maximum):-

$$\eta_{max} = \frac{P_{max}}{E * A_c} \times 100 \%$$

$P_{max}$  = Maximum Power Output (in W)

$E$  = incident radiation flux (in W/m<sup>2</sup>)

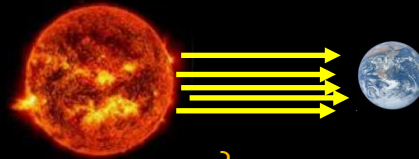
$A_c$  = Area of Collector (in m<sup>2</sup>)



Land Coverage

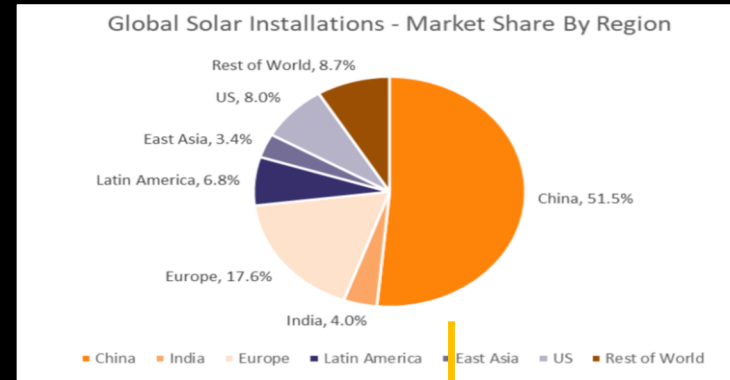
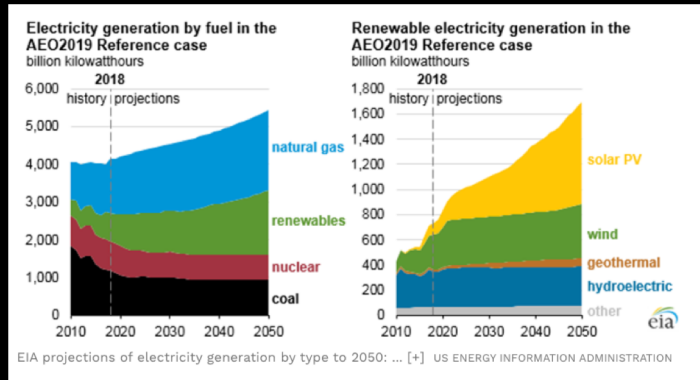


- The Earth receives 174 petawatts (10<sup>15</sup>) (PW) of incoming solar radiation (insolation) at the upper atmosphere.



- About 30% is reflected back to space while the rest, 123 PW, is absorbed by clouds, oceans and land masses.
- In 2022 solar photovoltaic PV generated 4.5% (1284 TWh) of the world's electricity compared to 1% (253 TWh) in 2015. Wind and solar generated over 12% of the world's electricity in 2022

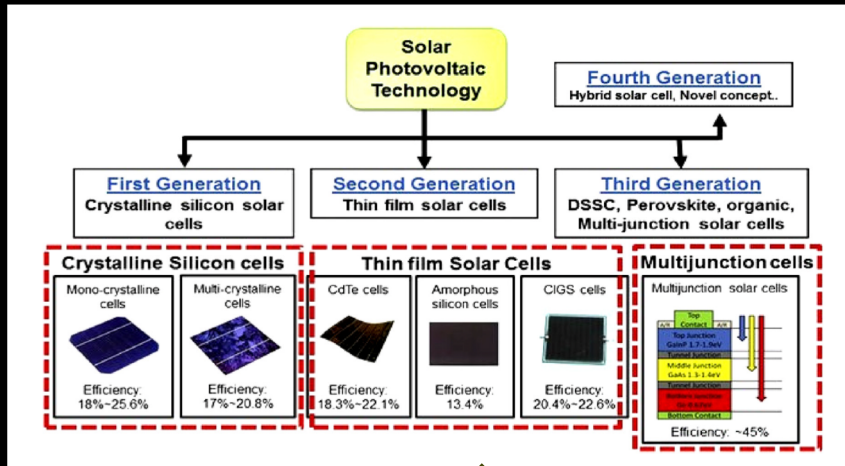
# Harvesting UV Radiation from the Sun in 2023



The Sustainable City in Dubai, United Arab Emirates Produce 87% of its needed energy over 114-acre



# Solar Photovoltaic Technologies

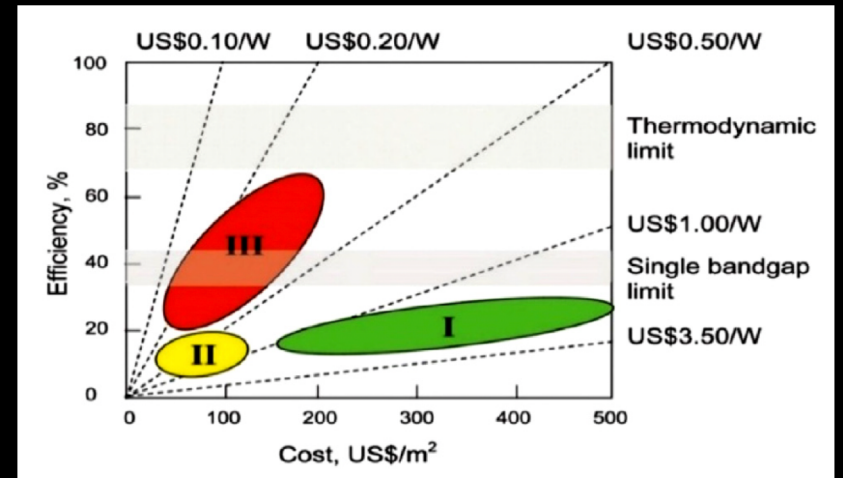
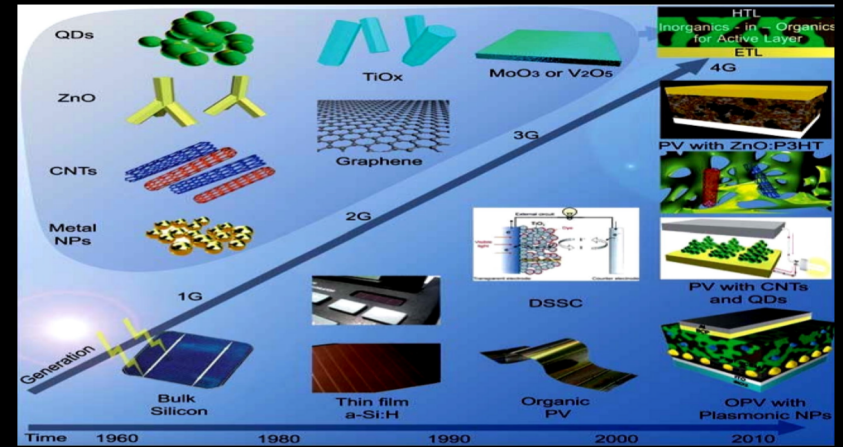


Generations

Efficiency

Evolution

Cost



## Conclusions

The development of radiation detectors and imaging technologies has always been a crucial component in scientific discoveries. Silicon being one of the most abundant element on earth still has a great potential in being a big player in sustainable solutions for the future.

By making the unseen “visible”, these detectors not only expand our understanding of the natural world but also pave the way for innovations that improve and advance human life.



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